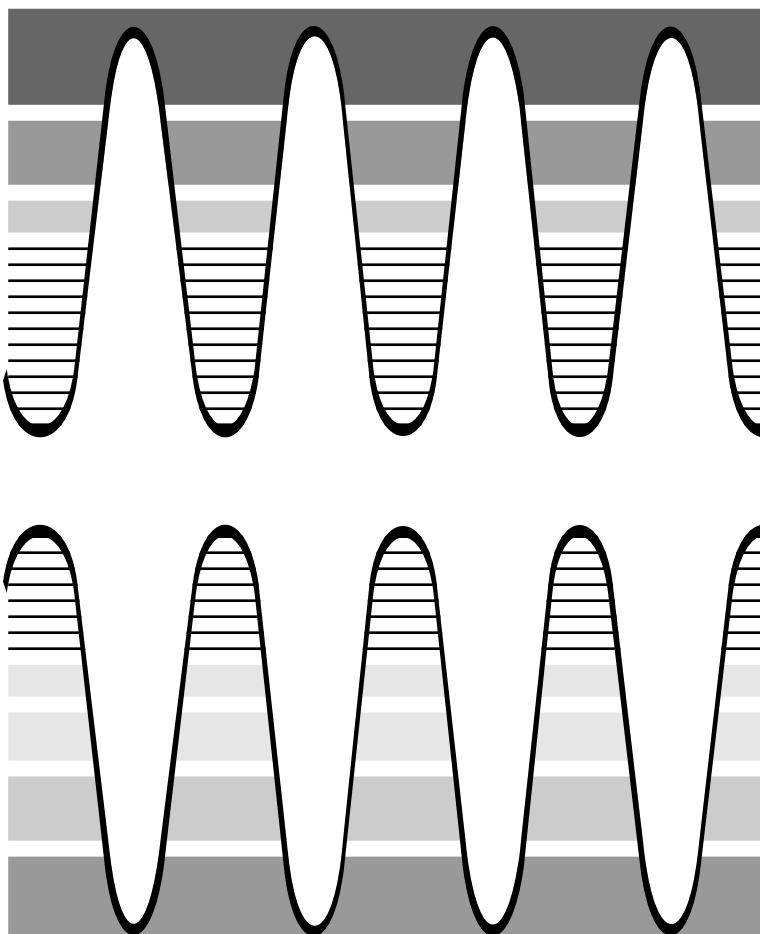


TMS
Minerals • Metals • Materials

University of California
Santa Barbara, California
June 30 – July 2, 1999



**41st
ELECTRONIC
MATERIALS
CONFERENCE**

June 30 - July 2, 1999

**ADVANCE PROGRAM
Includes Housing & Registration Forms**

<http://www.tms.org/Meetings/Specialty/EMC99/EMC99.html>

TMS

Minerals • Metals • Materials

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Schedule of Events

41st Electronic Materials Conference

Tuesday, June 29, 1999

Registration 3:00PM-8:00PM

Location University Center/Multicultural Lounge

Wednesday, June 30, 1999

Registration 7:30AM-5:00PM

Location University Center/Multicultural Lounge

Exhibit Booths 10:00AM-5:00PM & 7:00PM-9:00PM

Location University Center/Lagoon Plaza

Welcome Reception 7:00PM-9:00PM

Location University Center/Lagoon Plaza

Plenary Session 8:30AM
(Including Student Awards Ceremony)

Location University Center/Corwin Pavilion

Speaker Dr. Shuji Nakamura

Session A. Semiconductor Quantum Dots - Devices 10:00AM

Session B. Materials Integration - Substrate Fabrication & Bonding 10:00AM

Session C. Characterization, Growth & Properties of Organic Electronic Materials 10:00AM

Session D. Oxides for Devices 10:00AM

Session E. Special Topical Session 1:30PM

Session F. Semiconductor Quantum Dots-Formation & Structure 1:30PM

Session G. Epitaxy for Devices-B 1:30PM

Session H. Electronic Transport in Organic & Molecular Materials 1:30PM

Session I. Column IV Heterostructures & Devices 1:30PM

Thursday, July 1, 1999

Registration 7:30AM-4:00PM

Location University Center/Multicultural Lounge

Exhibit Booths 10:00AM-4:00PM

Location University Center/Lagoon Plaza

Picnic: Evening at the Zoo 6:00PM-9:00PM

Location Santa Barbara Zoological Gardens

Session J. Epitaxy for Devices-A 8:20AM

Session K. Nanoscale Characterization 8:20AM

Session L. Wide Bandgap AlGaIn/GaN Heterostructures 8:20AM

Session M. SiC Growth & Characterization 8:20AM

Session N. Infrared Materials & Devices 8:20AM

Session O. Issues for Ferroelectric & High Permittivity Thin Film Materials 8:20AM

Session P. Ordering in Semiconductor Alloys 1:30PM

Session Q. Nanostructure Self-Assembly 1:30PM

Session R. Properties of InGaIn Heterostructures & Devices 1:30PM

Session S. Silicon Carbide Processing for Devices 1:30PM

Session T. Materials Integration: Growth & Characterization 1:30PM

Session U. Thermophotovoltaic Materials & Devices 1:30PM

Session V. Thermoelectric & Other Narrow Gap Materials 1:30PM

Friday, July 2, 1999

Registration 7:30AM-10:00AM

Location University Center/Multicultural Lounge

Session W. Epitaxy of III-V 8:30AM

Session X. Composite Materials & Applications 8:20AM

Session Y. Properties of Quantum Wires & Wells 8:20AM

Session Z. Wide Bandgap Nitrides (MBE, Theory & AlN) 8:20AM

Session AA. Metal Contacts to Wide Band Gap Semiconductors 8:20AM

Session BB. Etching & Passivation of Compound Semiconductors 8:20AM

Session CC. Defects & Defect Engineering for Devices 8:20AM

Session DD. Non-Destructive Testing & "In-Situ" Monitoring/Control 1:30PM

Session EE. Semiconductor Quantum Dots-Electronic Structures 1:30PM

Session FF. Issues of Dopants & Defects in Nitrides 1:30PM

Session GG. Epitaxy of II-VI & Chalcopyrites 1:30PM

Session HH. Epitaxy of Si, III-V, Oxides 1:30PM

1999 ELECTRONIC MATERIALS CONFERENCE

University of California
Santa Barbara, California
June 30 – July 2, 1999

<http://www.tms.org/Meetings/Specialty/EMC99/EMC99.html>

ADVANCE PROGRAM

Includes Housing and Registration Forms

GENERAL INFORMATION

EMC Registration and Housing forms included in the center of this brochure.

EARLY HOUSING AND REGISTRATION ARE ADVISED.

DATE AND LOCATION: The 41st Annual Conference of the Electronic Materials Committee of The Minerals, Metals & Materials Society will be held at the University of California, Santa Barbara, California, June 30 – July 2, 1999. This conference is being coordinated with the Device Research Conference of IEEE, which will take place June 28 – 30, 1999, at the same location.

For information regarding the 1999 Electronic Materials Conference, please contact:

Thomas F. Kuech, General Chairman
University of Wisconsin
Department of Chemical Engineering
1415 Engineering Drive
Madison, WI 53711
Telephone: 608-263-2922
Fax: 608-265-4036
E-mail: kuech@engr.wisc.edu

Michael R. Melloch, Program Chairman
School of Electrical and Computer Engineering
Purdue University
1285 Electrical Engineering Building
West Lafayette, IN 47907-1285
Telephone: 765-494-3528
Fax: 765-494-6441
E-mail: melloch@ecn.purdue.edu

CONFERENCE REGISTRATION: All attendees are encouraged to register in advance to avoid delays in registering at the Conference. Both Electronic Materials Conference (EMC) and Device Research Conference (DRC) badges will be accepted by both Conferences on Wednesday, June 30. Advance registration fees are: full conference \$325; one day \$275; student \$150.

Registration fee includes Welcoming Reception, Coffee Breaks, Thursday Picnic, attendance to all Technical Sessions and Exhibition. One-day fee does not include picnic.

To advance register, complete the registration form provided in the center of this mailer. **Advance registration will be accepted until June 7, 1999.** For questions on advance registrations, please contact TMS Customer Service at Telephone: 724-776-9000 ext. 270; Fax: 724-776-3770; or E-mail: csc@tms.org

You may register at the Conference. On-site registration will be located in the University Center/Multicultural Lounge and will begin on Tuesday afternoon and will continue Wednesday morning through Friday morning during the following hours and location.

Tuesday, June 29..... 3:00PM-8:00PM
Location: University Center/Multicultural Lounge

Wednesday, June 30..... 7:30AM-5:00PM
Location: University Center/Multicultural Lounge

Thursday, July 1..... 7:30AM-4:00PM
Location: University Center/Multicultural Lounge

Friday, July 2..... 7:30AM-10:00AM
Location: University Center/Multicultural Lounge

MESSAGES: A telephone and message board will be located near the Registration Desk in the Multicultural Lounge. Messages will be posted in this area throughout the Conference. Messages will also be posted in the Residence Halls. If you are residing on campus, you will receive the appropriate number to be used in an emergency in your housing packet.

REFUND POLICY: A written request must be sent to TMS Headquarters, 184 Thorn Hill Road, Warrendale, PA 15086, postmarked no later than June 7, 1999. A \$50 processing fee will be charged on all cancellations. NO refunds will be issued after the deadline date.

CAMPUS SMOKING POLICY: UCSB prohibits smoking in its buildings. Smoking will be allowed only in outdoor areas including breezeways and patios.

TECHNICAL SESSIONS: The Electronic Materials technical program will commence at 8:30AM on Wednesday, June 30. Sessions will be held on grounds at the University of California in the University Center. University Center/Corwin Pavilion will be the location of the conference plenary session. Session and paper titles are included in this brochure.

LATE NEWS PAPERS: Late news papers will be considered. Authors must submit the abstract by June 10, 1999, using the TMS Conference Management System (CMS). CMS can be accessed by the website at <http://www.tms.org/cms>. If you have questions or need assistance while using the CMS, please contact TMS Technical Programming Services at 724-776-9000 Ext. 227 or 237. Authors of accepted papers will be notified before the EMC Conference.

TECHNICAL EXHIBIT: In addition to a very strong program, EMC is having an exhibition of electronic materials technology and related services. It is an opportunity for EMC at-

tendees to meet these providers and acquaint themselves with their capabilities and products. You are encouraged to visit the tabletop exhibits and interact with the participating vendors.

Exhibit Location: University Center/Lagoon Plaza

Exhibit Dates and Hours:

Wednesday, June 30 10:00AM-5:00PM
& 7:00PM-9:00PM

Thursday, July 1 10:00AM-4:00PM

NOTE: Companies interested in participating in this exhibit should contact TMS for details and exhibitor information at the following address, telephone, fax or email:

Cindy Wilson
TMS/EMC Technological Exhibit
184 Thorn Hill Road
Warrendale, PA 15086-7514
Telephone: 724-776-9000, ext. 231
Fax: 724-776-3770
E-mail: wilson@tms.org

AMERICANS WITH DISABILITIES ACT: TMS strongly supports the federal Americans with Disabilities Act (ADA) which prohibits discrimination against, and promotes public accessibility for those with disabilities. In support of and compliance with this Act, we ask that those requiring specific equipment or services as an attendees of the Electronic Materials Conference to indicate your needs on the enclosed housing and registration forms.

POLICY ON AUDIO AND VISUAL RECORDING OF TECHNICAL PAPER PRESENTATIONS/SESSIONS: The Minerals, Metals & Materials Society (TMS) reserves the rights to any audio and video reproduction of all presentations at every TMS sponsored meeting. Recording of sessions (audio, video, still photography, etc.) intended for personal use, distribution, publication, or copyright without the express written consent of TMS and the individual authors is strictly prohibited.

ON-CAMPUS HOUSING ACCOMMODATIONS

We are pleased to invite EMC attendees to reside on the seaside campus of UCSB. Santa Barbara is a summer resort area and accommodations can be difficult to secure. Therefore, early registration and reservations are essential. On-campus accommodations will be available on a first request basis. UCSB residence halls and dining facilities are located within a 5-10 minute walk from the meeting rooms. Residence hall accommodations are either single or double occupancy, with single rooms reserved on a first request basis. Lodging includes beds made on arrival day and daily room service with washcloth and towel change. Restroom and shower facilities are located on each floor. Phone lines are available in the EMC Residence Halls; you may bring your own phone or you can purchase an inexpensive phone at the University Book Store. Also, calling card accessible phones are within the Hall lobby.

The Residence Hall cannot provide a wake-up service, so you may wish to bring an alarm clock as well.

Please check the hotel listings in the Off-Campus Housing section of this brochure.

We offer the following package plans to provide planning flexibility and the option to attend both DRC and EMC. All residence hall package plans include full meal service. Residence hall rooms without meals are not available. No adjustments for lodging or meals will be made for late arrival or early departure from the chosen package.

Please indicate your plan preference on the enclosed reservation form and return it with your payment to:

Sally Vito
EMC
Campus Conference Services
University of California
Santa Barbara, CA 93106-6120
Telephone: 805-893-3072
Fax: 805-893-7287
E-mail: svito@housing.ucsb.edu

Confirmation of reservation received by May 30, 1999 will be sent to you by the Conference Office. Prepayment for the anticipated number of nights is required.

Meals will be served in the De La Guerra Dining Commons during the following hours:

Breakfast 7:00AM-8:00AM
Lunch 11:45AM-1:15PM
Dinner 5:30PM-7:00PM

NOTE: Food facilities on campus close at 7:00PM.

Plan A: Includes lodging Tuesday through Thursday nights and the following 9 meals:

Tuesday dinner;
Wednesday .. breakfast, lunch and dinner;
Thursday breakfast, lunch and dinner/evening at the zoo (no dining commons meal offered Thursday night);
Friday breakfast and lunch.

NOTE: this package includes dinner on your arrival day.

Single Occupancy \$278.00
Double Occupancy \$237.00

Plan B: Includes lodging Wednesday and Thursday nights and the following 7 meals:

Wednesday .. lunch and dinner;
Thursday breakfast, lunch and dinner/evening at the zoo (no dining commons meal offered Thursday night)
Friday breakfast and lunch.

Single Occupancy	\$216.00
Double Occupancy	\$189.00

Plan C: (for those planning to attend DRC and EMC)
Includes lodging Sunday through Thursday nights and the following 14 meals:

- Sunday dinner;
- Monday breakfast, lunch and dinner;
- Tuesday breakfast, lunch and dinner (*DRC Beach Event included in DRC Registration Fee*);
- Wednesday .. breakfast, lunch and dinner;
- Thursday breakfast, lunch and dinner/evening at the zoo (no dining commons meal offered Thursday night)
- Friday breakfast and lunch.

NOTE: This package includes dinner on your arrival day.

Single Occupancy	\$383.00
Double Occupancy	\$315.00

LATE DEPARTURE

Friday Night (July 2) Room Rate: (includes lodging Friday evening and the following meals:

- Friday dinner
(*breakfast & Lunch included in main packages*)
- Saturday breakfast

NOTE: Checkout is Saturday, 11:00AM

Single Occupancy	\$60.00
Double Occupancy	\$47.00

COMMUTER LUNCH PACKAGE:

I plan to make off-campus housing arrangements directly with the hotel/motel and wish to purchase a commuter lunch package for on-campus meals.

Three (3) lunches	\$21.75
Five (5) lunches	\$36.25

NOTE: It is important to apply early.

NO REFUNDS WILL BE MADE FOR LATE ARRIVALS, EARLY DEPARTURES, OR MISSED MEALS

Method of Payment:

Payment is U.S. dollars may be made by:

- Personal Check or Money Order. Checks must be drawn on a U.S. Bank and should be made payable to "U.C. Regents".
- Credit Card: Visa or MasterCard

OFF-CAMPUS HOUSING

Blocks of rooms have been reserved, at special conference rates, for the hotels listed below. Rooms will be released as early as mid-May. Thereafter, reservations can be obtained only on a space available request. Please contact the hotel directly by mail, phone or fax as soon as possible. Rooms are available for either DRC, EMC or both, Sunday through Thursday nights, and **you must identify yourself as either a DRC or EMC attendee**. You can also stay Friday or Saturday night if you request it at the time you make your reservations, however, **the special rates below DO NOT apply to weekend rates. Friday and Saturday rates will be higher. Please note that the following rates DO NOT include 10% tax.**

Hotels located in Goleta approximately 4 – 5 miles from campus (7-10 minutes driving time)

Best Western South Coast Inn

5620 Calle Real

Goleta, CA 93117

Phone: 805-967-3200

Fax: 805-683-4466

\$89 single/double (Sunday-Thursday night)

Complimentary Continental Breakfast daily 6:00AM – 10:00AM Complimentary beer and wine Monday through Thursday, 5:00PM – 7:00PM available in the lobby.

Complimentary use of nearby athletic club. Rooms equipped with refrigerators, coffee makers and hair dryers. Complimentary airport shuttle provided from 7:30AM – 10:30PM.

Holiday Inn

5650 Calle Real

Goleta, CA 93117

Phone 805-964-6241

Fax: 805-964-8467

Reservation Code: 2DRC or 2EMC

\$84 single/double (Sunday – Thursday night)

Beautifully renovated spring 1996; full service restaurant; heated pool in palm garden setting. Holiday Inn's nationally recognized high service standards; complimentary airport shuttle between 6:00AM – 10:00PM.

Ramada Limited

4770 Calle Real

Santa Barbara, CA 93110

Phone: 805-964-3511

Fax: 805-964-0075

\$60 single; \$10 each additional person (Sunday – Thursday night)

Complimentary Buffet-style Continental Breakfast included; hotel provides complimentary taxi service to and from the airport per room as well as complimentary athletic club privileges.

The following hotel is located off the main entrance onto campus (3 minute driving time):

Pacifica Suites

5490 Hollister Avenue

Goleta, CA 93117

Phone: 805-683-6722

Fax: 805-683-4121

\$89/1; \$99/2

Complimentary cooked-to-order breakfast daily, complimentary evening beverages Monday – Saturday. Heated pool and spa. Complimentary airport shuttle 7:00AM – 7:00PM with 24 hour notice.

The following hotels are located in Santa Barbara:

El Encanto Hotel and Garden Villas

1900 Lasuen Road

Santa Barbara, CA 93103

Phone: 805-687-5000

Fax: 805-687-3903

\$139 single

Nestled in the foothills of Santa Barbara and overlooking the Pacific Ocean, the historic El Encanto Hotel features garden villas and cottages – many with wood-burning fireplaces, private patios or balconies and an elegant dining room with outdoor terraces. Charter member of Historic Hotels of America.

The Upham Victorian Hotel and Garden Cottages

1404 De La Vina Street

Santa Barbara, CA 93101

Phone: 805-962-0058

Fax: 805-963-2825

\$90 single

All rates include a deluxe continental breakfast, afternoon refreshments of fruit, wine and cheese and Oreo cookies and milk in the evening.

The following hotel is located in Montecito:

Montecito Inn

1295 Coast Village Road

Montecito, CA 93108

Phone: 805-969-7854

Fax: 805-969-0623

\$120 single/double

Complimentary Continental Breakfast. Pool, Jacuzzi, sauna and exercise room.

Montecito Café and lounge located on site.

WELCOMING RECEPTION: All attendees are invited to attend a hosted Welcoming Reception on Wednesday, June 30 from 7:00PM-9:00PM in the University Center Lagoon Plaza.

EVENING AT THE ZOO: On Thursday, July 1, conference attendees and their guests will have the opportunity to enjoy a catered dinner at the spectacular Santa Barbara Zoological Gardens overlooking the Pacific Ocean. All of the animals will be left out late for this event and a miniature train will circle the zoo throughout the evening allowing guests to enjoy the panoramic view of the Pacific Ocean as well as the mountains. Small children will delight in carousel rides early in the evening!

The cost of this event is included in the full conference and student registration fee. It is not included in the one-day registration fee.

The cost for one-day registrants and guests is \$55 for adults and \$20 for children 12 and under. You may order tickets for this event on the registration form. You are encouraged to purchase your tickets in advance. Tickets will be available at the registration desk at the conference. Deadline for ticket sales will be Noon on Wednesday, June 30, 1999.

INFORMAL COFFEE BREAKS: During the intermission of morning and afternoon sessions (at approximately 10:00-10:20AM and 3:10-3:30PM) coffee, tea, assorted pastries and sodas will be served in the University Center Lagoon Plaza, location of exhibits.

TRANSPORTATION: The Santa Barbara area may be reached by:

CAR: Santa Barbara lies on US 101, some 120 miles north of Los Angeles International Airport and 330 miles south of San Francisco International Airport. The University of California Santa Barbara campus is located on its own beaches some 10-15 miles north of Santa Barbara. To reach UCSB from Santa Barbara, drive north on US 101 and take Highway 217, UCSB – airport Exit. When driving south on US 101 (from San Francisco), take the Storke Rd – UCSB exit, travel about 1 mile on Storke, turning left onto El Colegio road which leads directly onto campus. When entering campus, stop at the campus gate and request directions to the Residence Hall if you will be residing on campus. If you are staying off-campus and only need to register for the conference, please request directions to the University Center which will be open during the specified Conference Registration hours indicate in this brochure.

BUS: Greyhound bus lines provide substantial service from Los Angeles and San Francisco. The local station is in downtown Santa Barbara. MTD bus service and taxi service are available from the terminal to campus.

TRAIN: Amtrak provides daily service from San Francisco and Los Angeles. The station is located in downtown Santa Barbara. Taxi service is available from the terminal to campus.

AIR: Santa Barbara Airport is adjacent to the University and is served by American Airlines and currently five commuter airlines (United Express, American Eagle, Skywest/Delta, American West, USS Air Express). See announcement in this brochure for special fares offered by US Airways for EMC/DRC. UCSB offers complimentary shuttle service from the airport. The vehicle will be marked UCSB Conferences Shuttle. Pick-up will be in front of the terminal or near the baggage area. If you don't see the shuttle vehicle, call 893-2189 or 893-2469. **The UCSB shuttle service is only provided for those attendees staying on campus.** If you will be staying in a hotel, you will need to contact them for shuttle information.

TAXI: Taxi service is available from the Airport to the local hotels not offering free shuttle service.

PARKING: Parking at UCSB is by permit only. Parking is complimentary for those residing on-campus in the Residence Hall. When you arrive at UCSB you can receive directions and a temporary parking permit from the gate attendant by identifying yourself as an Electronic Materials Conference (EMC) attendee. This temporary permit will need to be replaced with the permit you will receive at the Residence Hall.

Attendees residing off-campus may purchase a daily permit from the gate attendant for \$5 or purchase a 4-day permit (Tuesday through Friday) for \$12 at registration. However, pre-purchasing of parking permits is encouraged to eliminate standing in lines. See Housing Reservation Form to pre-purchase permit.

Parking citations are issued for failure to display permits and/or parking in incorrect areas.

RECREATION: The University Recreation Center is open Monday through Saturday. Equipment includes racquetball and squash courts, weight training rooms, and 3 swimming pools. The cost of a Recreation Center pass is \$3.50/adult/day. Passes can be purchased at the campus Conference Service Office or at the Conference Registration Desk. Consult with the Residence Halls desk attendant for hours. Those EMC participants residing on campus may also check out recreational equipment (volleyballs, basketballs, frisbees, billiard, and pingpong equipment) from the service desk by presenting your room key to the Desk Attendant. Goleta public beach is accessible by a short walk from the East Gate of the campus and is open from dawn to dusk. The University beach, east and south of the campus, is directly accessible from the residence halls.

ABOUT SANTA BARBARA: The city of Santa Barbara, founded by the Spanish in the 18th century, is considered to be one of the jewels of the California coast. It lies approximately 100 miles northwest of Los Angeles, nestled against the Santa Ynez Mountains and overlooking the Pacific Ocean. In June, the days are warm (70s) and the nights are cool (50s), with occasional morning fog. Nearby are many excellent ocean beaches, lakes, forests, mountains with varied hiking trails, and such man-made attractions as the Hearst Castle, the flower fields of Lompoc, the Old World Danish Village of Solvang, the Mission, Court House, and other examples of Spanish architecture.

DRESS: Casual clothing is in order with a sweater or light jacket occasionally needed for the evenings. UCSB is essentially a walking campus, so be sure to wear comfortable walking shoes.

For additional information regarding the University of California Santa Barbara housing, please contact:

Sally Vito
UCSB Campus Conference Services
Santa Rosa Administrative Center
University of California
Santa Barbara, CA 93106-6120
Phone: 805-893-3072
Fax: 805-893-7287
E-mail: svito@housing.ucsb.edu

STUDENT TRAVEL ASSISTANCE: Student authors who plan to present a paper at the 1999 Electronic Materials Conference may be eligible for travel assistance depending on the particular circumstances involved. To apply for student travel assistance, submit an application no later than June 12, 1999 to:

Thomas F. Kuech, General Chairman
University of Wisconsin
Department of Chemical Engineering
1415 Engineering Drive
Madison, WI 53711
Phone: 608-263-2922
Fax: 608-265-4036
E-mail: kuech@engr.wisc.edu

STUDENT AWARDS: Three \$500 student awards are given annually by the Electronic Materials Committee for the best presentations by students at the conference. Student papers will be judged on both scientific content and presentation at the Electronic Materials Conference.

Awards will be presented during the plenary session on Wednesday, June 30, in the Corwin Pavilion.

PUBLICATION OF CONFERENCE PAPERS: There are no formal conference proceedings, but the conference abstracts will be published in the Journal of Electronic Materials. We also encourage you to submit manuscripts on your work to the Journal of Electronic Materials. There are three special issues of the Journal of Electronic Materials scheduled with manuscript due dates shortly after the conference that might be of particular interest to conference participants. Those special issues are:

“Compliant and Alternative Substrates”

There will be a special issue of the Journal of Electronic Materials dedicated to recent advances in the area of compliant and alternative substrates. This special issue is scheduled for publication in July 2000. Information for authors may be found on the inside back cover of current issues of the journal. The final date for submission of manuscripts is September 10, 1999. Papers are solicited in the areas of compliant and alternative substrate design, fabrication, and modeling, as well as applications of these substrates to lattice-mismatched epitaxy and devices.

Original manuscripts with original figures suitable for reproduction, two copies of the manuscript, and a completed copyright form should be submitted to one of the co-editors at the addresses below:

Matthew L. Seaford
Air Force Research Lab
Materials and Manufacturing Directorate
3005 P. Street, Suite 6
Building 62, Room 132
WPAFB, OH 45433-7707
Phone: 937-656-5708
Fax: 937-656-7788
e-mail: seaforml@ml.wpafb.af.mil

Peter Moran
University of Wisconsin
Department of Chemical Engineering
1415 Johnson Drive
Madison, WI 53706
Phone: 608-265-6779
Fax: 608-265-8963
e-mail: pmoran@itis.com

Thomas F. Kuech
University of Wisconsin
Department of Chemical Engineering
1415 Engineering Drive
Madison, WI 53711
Phone: 608-263-2922
Fax: 608-265-4036
e-mail: kuech@enr.wisc.edu

Theresa Mayer
Penn State University
Department of Electrical Engineering
111K Electrical Engineering West
University Park, PA 16802
Phone: 814-863-8458
Fax: 814-865-7065
e-mail: tsm2@psu.edu

“Quantum Dots”

There will be a special issue of the Journal of Electronic Materials dedicated to quantum dots. This special issue is scheduled for publication in April 2000. Information for authors may be found on the inside back cover of current issues of the journal. The final date for submission of manuscripts is September 1, 1999. Papers are solicited in areas of quantum dot formation, processing, device applications, and electrical, optical and structural characterization.

Original manuscripts with original figures suitable for reproduction, two copies of the manuscript, and a completed copyright form should be submitted to one of the co-editors at the addresses below.

Prof. Supriyo Bandyopadhyay
Dept. of Electrical Engineering
University of Nebraska
Lincoln, NE 68588-0511
phone: 402-472-0294
fax: 402-472-4732
email: bandy@quantum1.unl.edu

Prof. Clivia M. Sotomayor-Torres
Institute of Materials Science &
Dept of Electrical Engineering
University of Wuppertal
Gauss-Strasse 20
42097 Wuppertal
GERMANY
phone: 49-202-439-2920
fax: 49 -202- 439-3037
email: clivia@uni-wuppertal.de

Prof. Akio Sasaki
Osaka Electro-Communication Univ.
Department of Electronics
Neyagawashi 572, Japan
phone: 81-720-24-1131
fax.: 81-720-24-0014
email: sasaki@isc.osakac.ac.jp

“III-V Nitrides and SiC”

Because of the rapid advances in and technical importance of SiC and III-V nitride materials and devices, there will be a special issue of the Journal of Electronic Materials dedicated to these materials. This special issue is scheduled for publication in March 2000. Information for authors may be found on the inside back cover of current issues of the journal. The final date for submission of manuscripts is August 1, 1999. Papers are solicited in areas of epitaxy, processing, device applications, and electrical, optical and structural characterization. This will be the sixth such special issue in the Journal of Electronic Materials. If the trend of increasing number of submissions continues, two special issues may be published, one on III-V Nitrides and one on SiC.

Original manuscripts with original figures suitable for reproduction, two copies of the manuscript, and a completed copyright form should be submitted to the appropriate co-editor listed below.

III-V Nitride Editor

Ilesanmi Adesida
Microelectronics Laboratory
University of Illinois
208 N. Wright St
Urbana, IL 61801
phone: 217-244-6379
fax: 217-244-6375
email: adesida@capone.ccsu.uiuc.edu

SiC Editors

Michael R. Melloch
1285 Electrical Engineering Bldg.
Purdue University
West Lafayette, IN 47907-1285
phone: 765-494-3528
fax: 765-494-6441
email: melloch@ecn.purdue.edu

JOURNAL OF ELECTRONIC MATERIALS: The full conference member \$357, USA Nonmember \$475 and NON-USA Nonmember \$499 registration fees includes a subscription to the 2000 Journal of Electronic Materials which will include manuscripts of papers presented at the 1999 Electronic Materials Conference. Those who register for one day may order a subscription to the 1999 JEM on the registration form.

PROGRAM: A complete program with abstracts of papers to be presented at the meeting will be made available for all registrants at the time of registration.

Electronic Materials Committee

The Minerals, Metals & Materials Society

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JOHN BARDEEN AWARD



Lionel Kimerling
John Bardeen Award

The John Bardeen Award, established in 1994, recognizes an individual who has made outstanding contributions and is a leader in the field of electronic materials.

Recipient: *Lionel Kimerling*

Citation: *Professor Kimerling is a world leader in the field of defects in electronic materials.*

Lionel Kimerling is Thomas Lord Professor of Materials Science and Engineering and director of the Materials Processing Center at the Massachusetts Institute of Technology.

He earned his S.B. in metallurgy and his Ph.D. in materials science at the Massachusetts Institute of Technology in 1965 and 1969, respectively. He was a member of the technical staff at ATT Bell Laboratories from 1972 to 1981, at which time he became head of the Materials Physics Research Department at ATT Bell Laboratories. He joined the staff of Massachusetts Institute of Technology in 1990. He has also served as a lecturer at Aarhus University, Denmark, and Technion University, Israel.

Dr. Kimerling was the 1994 president of TMS and a past director of the TMS Electronic, Magnetic, & Photonic Materials Division. He is a member of the TMS Foundation Board of Trustees. He has received several honors, and is a fellow of the American Association for the Advancement of Science and the American Physical Society.

“TMS is the primary intellectual reservoir of the materials profession. Within TMS I have grown to appreciate the diversity of ideas and goals in the materials field. The annual TMS Electronic Materials Conference has been the testing ground for my research and a launch pad for its applications. I am grateful to be honored by my peers from who I have benefited so much.”



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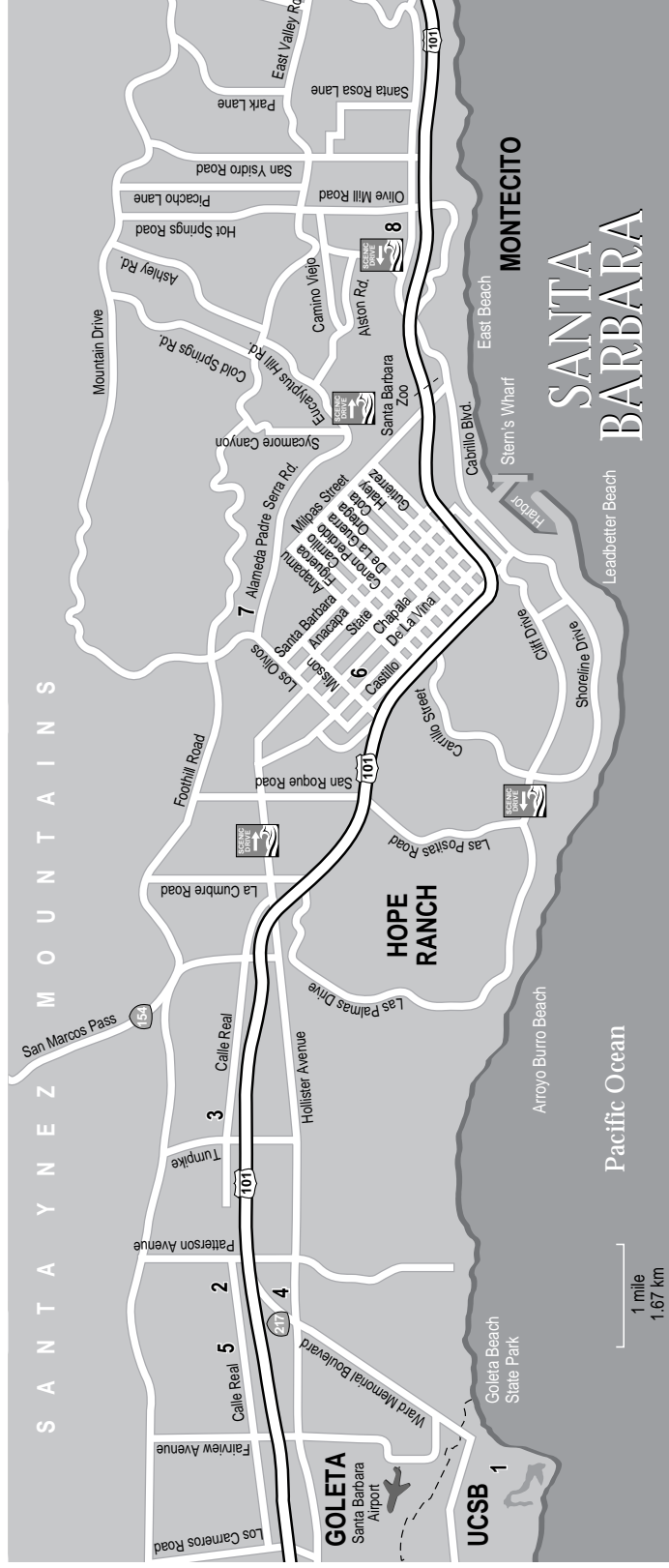
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You are encouraged to submit a nomination for the TMS John Bardeen Award. This award recognizes an individual who has made an outstanding contribution and is a leader in the field of electronic materials.

The award is named in honor of John Bardeen who, through a career of theoretical and experimental research, set the foundation for the current state of understanding of electronic materials. Two areas where Bardeen had great impact were the invention and development of the solid state transistor and the theory that developed greater understanding of superconductivity.

For award criteria and additional information, just pick up a nomination form at the TMS Registration desk at EMC, or you may download the nomination form from the TMS Homepage on the WWW at <http://www.tms.org>.



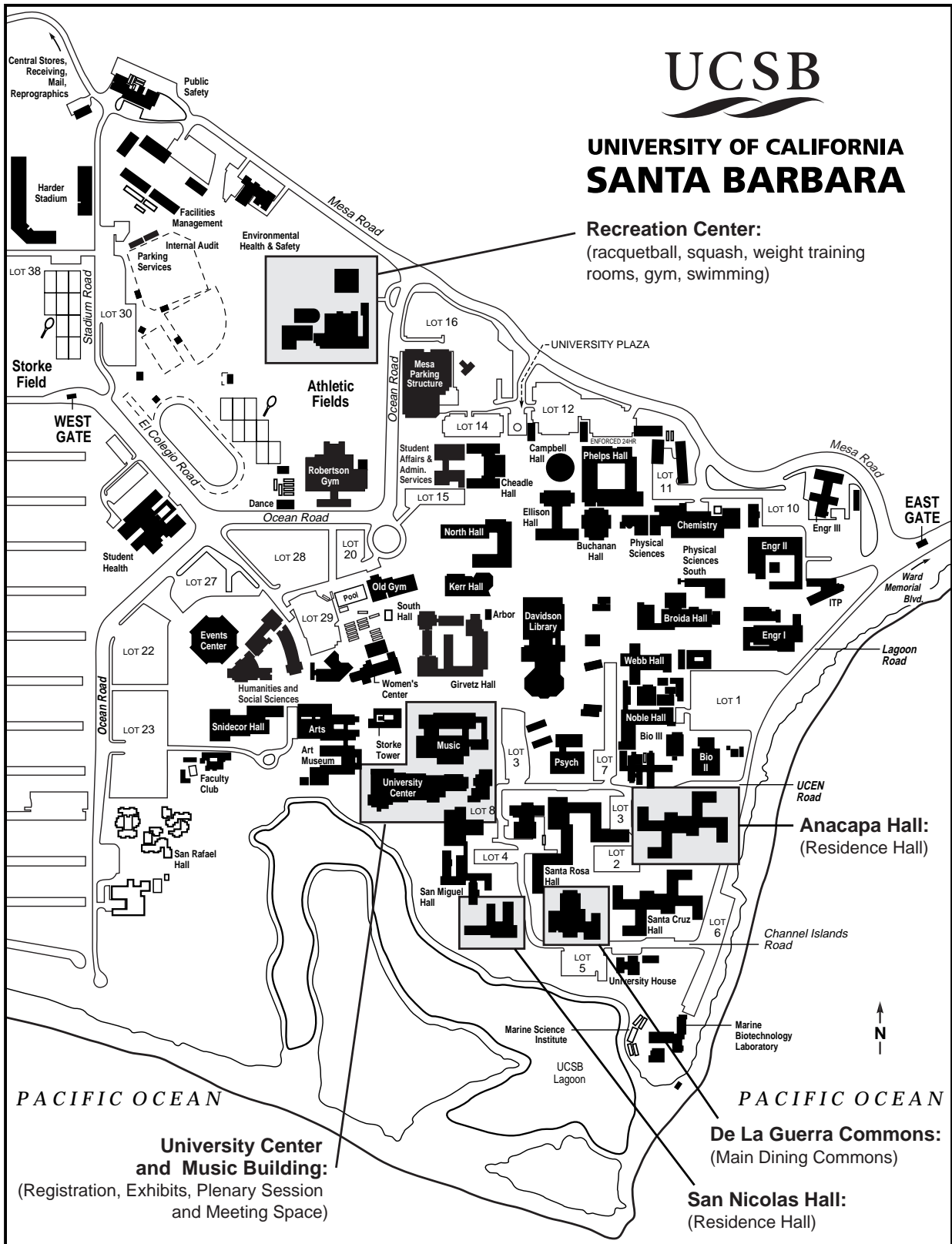
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TECHNICAL PROGRAM

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Wednesday, June 30, 1999

EMC PLENARY LECTURE/STUDENT AWARDS

Ceremony: 8:30 AM

Room: Corwin Pavalion

Session Chairman: Thomas Kuech, University of Wisconsin, Department of Chemical Engineering, Madison, WI 53706

Plenary Speaker:

Topic: Present and Future Prospects of InGaN-Based Blue LEDs and LDs: *Shuji Nakamura*¹; ¹Nichia Chemical Industries, Ltd., R&D Dept., 491, Oka, Kaminaka, Anan, Tokushima Japan

BREAK: 9:30 AM - 10:00 AM

Wednesday AM, June 30, 1999

Session A. Semiconductor Quantum Dots - Devices

Session Chairs: Kang Wang, University of California, Los Angeles, CA USA; Mark Miller, University of Virginia, Dept. of Elect. Eng., Charlottesville, VA USA

10:00 AM

Gain and Emission Characteristics of MOVPE Grown InP/GaInP Quantum Dot Lasers: *Thomas Riedl*¹; Joerg Porsche¹; Markus Ost¹; Ferdinand Scholz¹; Andreas Hangleiter¹; ¹University of Stuttgart, 4th Phys. Institute, Pfaffenwaldring 57, Stuttgart 70550 Germany

10:20 AM

4 Watt High Power Quantum Dot Lasers: *M. Grundmann*¹; Ch. Ribbat¹; M.-H. Mao¹; F. Heinrichsdorff¹; N. N. Ledentsov¹; D. Bimberg¹; A. R. Kovsh²; A. Yu. Egorov²; D. A. Lifshits²; M. V. Maximov²; Yu. M. Shernyakov²; V. M. Ustinov²; A. E. Zhukov²; Zh. I. Alferov²; ¹TU Berlin, Institute of Solid State Phys., PN 5-2, Hardenbergstr. 36, Berlin 10623 Germany; ²A. F. Ioffe Physico-Technical Institute, Polytechnicheskaya 26, St. Petersburg 194021 Russia

10:40 AM

Electroluminescence of Stacked In(Ga)As/GaAs QDs at 1.3 μm - 1.4 μm : *Frank Heinrichsdorff*¹; Nikolai Zakharov²; Peter Werner²; Alois Krost¹; Dieter Bimberg¹; ¹Technische Universität Berlin, Institut

für Festkörperphysik, Sekr. PN 5-2, Berlin 10623 Germany; ²Max-Planck-Institut für Mikrostrukturphysik, Weinberg 6, Halle, 06120 Germany

11:00 AM

Collisional Carrier Kinetics and Broadening of Spectral Lines in Quantum Dot Structures: *Alexander V. Uskov*¹; ¹Lebedev Physical Institute, Div. of Quantum Radio Physics, Leninsky pr 53, 117924 Moscow Russia

11:20 AM +

Direct Bandgap Materials for Monolithic Optical Interconnects on Silicon: *Victoria Ann Williams*¹; Alfred T. Schremer¹; Joseph M. Ballantyne¹; ¹Cornell University, Elect. Eng., Ithaca, NY 14850 USA

11:40 AM Late News

Wednesday AM, June 30, 1999

Session B. Materials Integration - Substrate Fabrication and Bonding

Session Chairs: Pete Moran, University of Wisconsin-Madison, Dept. of Chem. Eng., Madison, WI USA; Alan Doolittle, Georgia Institute of Technology, Atlanta, GA USA

10:00 AM +

Fabrication of Thin Film InGaN LED Membranes by Laser Liftoff: *William S. Wong*¹; Nathan W. Cheung²; Timothy D. Sands³; Michael Kneissl⁴; David P. Bour⁴; Ping Mei⁴; Linda T. Romano⁴; Noble M. Johnson⁴; ¹University of California, Dept. of Mats. Sci. and Min. Eng., 211-181 Cory Hall, #1772, Berkeley, CA 94720-1772 USA; ²University of California, Dept. of Elect. Eng. and Comp. Sci., 513 Cory Hall, Berkeley, CA 94720 USA; ³University of California, Dept. of Mats. Sci. and Min. Eng., 559 Evans Hall, Berkeley, CA 94720-1760 USA; ⁴Xerox PARC, Electr. Mats. Lab., 3333 Coyote Hill Rd., Palo Alto, CA 94304 USA

10:20 AM +

GaN LEDs Transferred to Copper Substrates Using Laser Assisted Debonding: *Philip R. Tavernier*¹; Monica C. Hansen¹; Steve P. DenBaars¹; David R. Clarke¹; ¹University of California Santa Barbara, Dept. of Mats., Bldg. 503 Rm. 1355, Santa Barbara, CA 93106-5050 USA

10:40 AM +

A Comparison of Wet and Dry Chemistries for Hydrophobic Silicon Wafer Bonding: *James B. Mattzela*¹; Paul A. Roman¹; Jerzy Ruzyllo¹; Theresa S. Mayer¹; ¹The Pennsylvania State University, Dept. of Elect. Eng., University Park, PA 16802

11:00 AM +

Deposition of Borosilicate Glasses by Low Pressure Chemical Vapor Deposition Using Tetraethylorthosilicate and Trimethylborate: *Darren Michael Hansen*¹; David Charters¹; Yee Au¹; Wai Mak¹; Wisnu Tejasukmana¹; Peter D. Moran¹; Thomas F. Kuech¹; ¹University of Wisconsin, Chem. Eng., 1415 Engineering Dr., Madison, WI 53706 USA

11:20 AM

Ion-Cutting of GaSb Wafers: *Y. Zheng*¹; Z. F. Guan¹; S. S. Lau¹; D. M. Hansen²; T. F. Kuech²; T. E. Haynes³; T. Hoechbauer⁴; M. Nastasi⁴; ¹University of California, San Diego, Dept. of Elect. and Comp. Eng., 9500 Gilman Dr., Mail Code 0407, La Jolla, CA 92093-0407 USA; ²University of Wisconsin-Madison, Dept. of Chem. Eng., Madison, WI 53706-1691 USA; ³Oak Ridge National Laboratory, Solid State Div., Oak Ridge, TN 37831 USA; ⁴Los Alamos National Laboratory, Mats. Sci. & Tech. Div., Los Alamos, NM 87545 USA

11:40 AM Late News

Wednesday AM, June 30, 1999

Session C. Characterization, Growth and Properties of Organic Electronic Materials

Session Chairs: Jianna Wang, Penn State University, Dept. of Elect. Eng., State College, PA USA; Rashid Bashir, Purdue University, School of Elect. and Comp. Eng., West Lafayette, IN USA

10:00 AM

Dependence of Emission Quantum Yield on Chain Packing in Electroluminescent Polymers: *Lewis J. Rothberg*¹; Christopher J. Collision¹; Rachel Jakubiak¹; Yi Li¹; Christine M. Liberatore¹; EdVin Soh¹; ¹University of Rochester, Dept. of Chem./NSF Center for Photo-induced Charge Transfer, Hutchison Hall 200, Rochester, NY 14627 USA

10:20 AM +

Near-Field Scanning Optical Microscopy of Conjugated Polymer Films: *Jessie A. DeAro*¹; Paul J. Carson¹; Jonathon Z. Sexton¹; Steven K. Buratto¹; ¹University of California, Santa Barbara, Chem. Dept., Santa Barbara, CA 93106 USA

10:40 AM

CPAFM: A Tool for Nanoscale Structure and Electronic Properties: *Tommie Wilson Kelley*¹; C. Daniel Frisbie²; ¹University of Minnesota, Chem. Eng. and Mats. Sci., 421 Washington Ave., SE, 151 Amundson Hall, P.O. Box 134, Minneapolis, MN 55455 USA; ²University of Minnesota, Chem. Eng. and Mats. Sci., 421 Washington Ave., SE, 151 Amundson Hall, Minneapolis, MN 55455 USA

11:00 AM +

Growth of Thermally Evaporated Pentacene Films on SiO₂:

*Jonathan Andrew Nichols*¹; David James Gundlach¹; Chris D. Sheraw¹; Darrell G. Schlom²; Thomas Nelson Jackson¹; ¹The Pennsylvania State University, Dept. of Elect. Eng., 121 Elect. Eng. East, University Park, PA 16802 USA; ²The Pennsylvania State University, Dept. of Mats. Sci. and Eng., 103 Steidle Bldg., University Park, PA 16802 USA

11:20 AM

Nanoscale Investigation of the Optical Properties of Tris-8-Hydroxyquinoline Aluminum Films (Alq₃):

*Grace M. Credo*¹; Steven K. Buratto¹; ¹UC Santa Barbara, Dept. of Chem., Santa Barbara, CA 93106-9510 USA

11:40 AM Late News

Wednesday AM, June 30, 1999

Session D. Oxides for Devices

Session Chair: Dan Dapkus, University of Southern California, Los Angeles, CA USA

10:00 AM +

Increased Lateral Oxidation Rates of AlInAs on InP Using Short-Period Superlattices:

*Eric Hall*¹; Andrew Huntington¹; Ryan Naone¹; Herbert Kroemer²; Larry A. Coldren²; ¹University of California, Santa Barbara, Mats. Dept., Santa Barbara, CA 93106 USA; ²University of California, Santa Barbara, ECE Dept., Santa Barbara, CA 93106 USA

10:20 AM +

As Overpressure Mediated Crystallinity Change of AlGaAs Compounds and its Application in Formation of Bragg Reflectors:

*Kuo-Lih Chang*¹; D. E. Wohlert¹; G. W. Pickrell¹; J. H. Epple¹; H. C. Lin¹; K. Y. Cheng¹; K. C. Hsieh¹; ¹University of Illinois at Urbana-Champaign, Dept. of Elect. and Comp. Eng., Urbana, IL 61801 USA

10:40 AM +

The Effect of an Oxide Aperature on the Base-Collector Capacitance of a GaAs Heterojunction Bipolar Transistor:

*James G. Champlain*¹; Umesh K. Mishra¹; ¹University of California, Elect. and Comp. Eng., Santa Barbara, CA 93106 USA

11:00 AM +

Electrical Properties of Al₂O₃ Gate Dielectric:

*Chin Chang Liao*¹; W. J. Chen; C. H. Lu¹; Albert Chin¹; C. Tsai¹; ¹National Chiao Tung University, Dept. of Electronics Eng., Hsinchu Taiwan; National Huwei Institute Tech, Dept. of Mech. Mats. Eng., Huwei Taiwan

11:20 AM Late News

11:40 AM Late News

Session E. Special Topical Session

Session Chairs: Jim Speck, University of California, Mats. Dept., Santa Barbara, CA USA; Richard Miles, SDL Inc., San Jose, CA USA

1:30 PM *Invited

Electron Microscope Studies Studies of Defects: D. Cherns

2:00 PM *Invited

The Technological Significance of Defects in III-Nitride Materials: *S. Jeffrey Rosner*¹; ¹Hewlett-Packard Laboratories, 3500 Deer Creek Rd., Palo Alto, CA 94303

2:30 PM *Invited

Lateral and Pendeo-Epitaxial Overgrowth and Defect Reduction of GaN Films: *Robert F. Davis*¹; O-H. Nam¹; Thomas Gehrke¹; Kevin J. Linthicum¹; Tsvetanka S. Zheleva¹; Pradeep Rajagopal¹; Darren B. Thomson¹; Chris A. Zorman²; Mehren Mehregany²; ¹North Carolina State University, Mats. Sci., Box 7907, Raleigh, NC 27695-7907 USA; ²Case Western Reserve University, Elect., Systems and Comp. Eng. and Sci., Cleveland, OH 44106 USA

3:00 PM *Invited

Effect of Native Point Defects on Nitride Materials and Devices: *Chris G. Van de Walle*¹; ¹Xerox PARC, 3333 Coyote Hill Rd., Palo Alto, CA 94304 USA

3:30 PM Break

3:50 PM *Invited

The Effect of Doping and Growth Stoichiometry on the Properties of Threading Dislocations in Gan: *Alan F. Wright*¹; Kevin Leung¹; ¹Sandia National Laboratories, Dept. 1113, MS 1415, P.O. Box 5800, Albuquerque, NM 87185-1415 USA

4:10 PM *Invited

Effects of Point Defects and Dislocations on Transport Properties of GaN: *David C. Look*¹; ¹Wright State University, Semiconductor Research Center, Dayton, OH 45435

4:40 PM *Invited

Lateral Epitaxial Overgrowth: S. P. Denbaars, University of California, Mats. Dept. Bldg. EII, Santa Barbara, CA 93110 USA

5:10 PM *Invited

Characterization of Nitride Semiconductor Heterostructures and Laser Diodes: *D. P. Bour*¹; M. Kneissl¹; L. T. Romano¹; C. G. Van deWalle¹; J. Northrup¹; N. M. Johnson¹; ¹XEROX Palo Alto Research Center, Electr. Mats. Laboratory, 3333 Coyote Hill Rd., Palo Alto, CA 94304

**Session F. Semiconductor Quantum Dots -
Formation and Structure**

Session Chairs: Ben V. Shanabrook, Naval Research Lab, Code 6870, Washington, DC USA; Craig Pryor, Pryor Consulting, Porterville USA

1:30 PM

Infrared Spectroscopy of Intraband Transition in Modulation Boron-Doped GeSi Quantum Dot Superlattices: *Wen-Gang Wu*¹; Yin-Sheng Tang²; ¹University of California/Los Angeles, Device Research Lab., Dept. of Elect. Eng., 56-125B EIV, Box 951594, Los Angeles, CA 90095-1594 USA; ²University of California/Los Angeles, Device Research Lab., Dept. of Elect. Eng., 56-125B EIV, Box 951594, Los Angeles, CA 90095-1594 USA

1:50 PM

Study of Phonons in Self-Organized Multiple Ge Quantum Dots: *Jianlin Liu*¹; Yinsheng Tang¹; Kang L. Wang¹; ¹University of California at Los Angeles, Dept. of Elect. Eng., Device Research Laboratory, Los Angeles, CA 90095-1594

2:10 PM

Raman Spectroscopy of the Topology of the InAs/GaAs Self-Assembled Quantum Dots: Yuri Alexander Pusep¹; ¹Federal University of Sao Carlos, DF, Via Washington Luis, km 235, Sao Carlos, Sao Paulo 13565-905 Brasil

2:30 PM

Microscopic Transient Photoluminescence of Site-Controlled InAs Dots: *Tetsuya Nishimura*¹; Tomonori Ishikawa¹; Shigeru Kohmoto¹; Kiyoshi Asakawa¹; Osamu Wada¹; ¹The Femtosecond Tech. Research Association, 5-5 Tokodai, Tsukuba, Ibaraki 300-2635 Japan

2:50 PM

Optical Properties of InAs/InP Self-Assembled Quantum Dots Grown by Metalorganic Chemical Vapor Deposition: *Euijoon Yoon*¹; Youngboo Moon¹; Tae-Wan Lee¹; Heedon Hwang¹; Sukho Yoon¹; Young Dong Kim²; Uk Hyun Lee³; Donghan Lee³; Hong-Seung Kim⁴; Jeong Yong Lee⁴; ¹Seoul National University, School of Mats. Sci. & Eng., Rm. 32-203, Seoul 151-742 Korea; ²Kyung Hee University, Dept. of Phys., Seoul Korea; ³Chungnam National University, Dept. of Phys., Taejon Korea; ⁴Korea Advanced Institute of Sci. & Tech., Dept. of Mats. Sci. & Eng., Taejon Korea

3:10 PM Break

3:30 PM

Fluorescence Intermittency and Quantum Efficiency of Individual Porous Silicon Nanoparticles: *Michael D. Mason*¹; Grace M. Credo¹; Steven K. Buratto¹; ¹University of California, Santa Barbara, Dept. of Chem., Goleta, CA 93106 USA

3:50 PM

Origin of Size Distribution in ZnSe Self-Organized Quantum Dots Grown on ZnS layers: *Takehiko Tawara*¹; Satoru Tanaka¹; Hidekazu Kumano¹; Ikuo Suemune¹; ¹Hokkaido University, Research Institute for Electr. Sci., Kita-12, Nishi-6, Kita-ku, Sapporo, Hokkaido 060-0812 Japan

4:10 PM

Structural Studies of Stacked InAs Quantum Dots in a Silicon Matrix Grown by MBE: N. D. Zakharov¹; *Peter Werner*¹; Victor M. Ustinov²; George E. Cirlin²; O. V. Smolski²; D. V. Denisov²; P. S. Kop'ev¹; Zh. I. Alferov²; N. N. Ledentsov²; Robert Heitz³; Dieter Bimberg³; ¹MPI of Microstructure Physics, Halle (Saale) D - 06120 Germany; ²A.F. Ioffe Physical-Technical Institute, St. Petersburg Russia; ³Technical University of Berlin, Berlin D-10623 Germany

4:30 PM

In-Situ Self-Organization of Two- and Three-Dimensional High-Density InAs Quantum Wire Arrays on (100) InP: *Hanxuan Li*¹; Theda Daniels-Race¹; Zhanguo Wang²; ¹Duke University, Dept. of Elect. & Comp. Eng., Durham, NC 27708-0291 USA; ²Institute of Semiconductors, Chinese Academy of Sciences, Laboratory of Semiconductor Mats. Sci., Beijing 100083 P. R. China

4:50 PM Late News

Wednesday PM, June 30, 1999

Session G. Epitaxy for Devices

Session Chairs: Ray Tsui, Motorola Labs, Tempe, AZ USA; Mike Tischler, Epitronics Corporation, Mesa, AZ USA

1:30 PM

Tellurium Memory Effects on OMVPE-Grown In_{0.3}Ga_{0.7}As_{0.997}N_{0.003}/GaAs Laser Diodes: *Nein-Yi Li*¹; Chris Hains¹; Jun Lu¹; Kai Yang¹; Julian Cheng¹; ¹University of New Mexico, Center for High Tech. Mats., 1313 Goddard Ave. SE, Albuquerque, NM 87106 USA

1:50 PM +

Investigation of P-Type GaInNAs for Heterojunction Bipolar Transistor Base Layers: *Huoping Xin*¹; Charles W. Tu¹; Peter M. Asbeck¹; Rebecca J. Welty¹; ¹University of California at San Diego, Dept. of Elect. and Comp. Eng., 9500 Gilman Drive, La Jolla, CA 92093-0407 USA

2:10 PM +

Growth and Characterization of Long Wavelength (1 Micron) GaInAsN Photo-detectors using Gas Source Molecular Beam Epitaxy: *Sudhir G. Subramanya*¹; Joachim Kruger¹; Piotr Perlin¹; Eicke R. Weber¹; Dan E. Mars²; Chris Kocot²; Ying-Lan Chang²; ¹University of California at Berkeley, Mats. Sci. and Min. Eng., 161M, 211-225 Cory Hall #1772, Berkeley, CA 94720-1772 USA; ²Hewlett Packard

Laboratories, 3500 Deer Creek Rd., B26M-7, Palo Alto, CA 94304 USA

2:30 PM

InGaAsN for High Efficiency Solar Cells Grown by Metalorganic Chemical Vapor Deposition: *Andrew A. Allerman*¹; Steven R. Kurtz¹; Eric D. Jones¹; James M. Gee¹; Rob M. Sieg¹; ¹Sandia National Laboratories, P.O. Box 5800, Albuquerque, NM 87185 USA

2:50 PM Late News

3:10 PM Break

3:30 PM +

AlGaAs and InGaAs-based Light Emitters on Si via Relaxed Graded GeSi Buffer Layers: *Michael E. Groenert*¹; Vicky K. Yang¹; Eugene A. Fitzgerald¹; ¹Massachusetts Institute of Technology, Dept. of Mats. Sci. and Eng., Rm. 13-4025, 77 Massachusetts Ave., Cambridge, MA 02139 USA

3:50 PM +

Lattice Matched Zn_xBe_{1-x}Te Films with GaAs and ZnSe for P-Contact Layers of ZnSe-based II-VI Laser Diodes: *M. W. Cho*¹; J. H. Chang¹; S. Saeki¹; K. Godo¹; H. Makino¹; T. Yao¹; ¹Tohoku University, Institute for Mats. Research, 2-1-1 Katahira, Sendai 980 Japan

4:10 PM

Selective InAs Contact to GaAs: *Kumar Shiralagi*¹; Ruth Zhang¹; Ray Tsui¹; ¹Motorola Labs, Physical Sciences Research Laboratories, 2100 East Elliot Rd., M/S-EL308, Tempe, AZ 85284 USA

4:30 PM +

Development of Multi-Functional InGaAs-Based Ohmic Contacts for GaAs Devices: *Mitsumasa Ogura*¹; Masanori Murakami¹; ¹Kyoto University, Dept. of Mats. Sci. and Eng., Kyoto Japan

4:50 PM

Use of Multi-Quantum Wells for Photoabsorption Enhancement in Compound Semiconductor Solar Cells: *Yoshitaka Okada*¹; Yoshiyuki Suzuki¹; Takatoshi Kikuchi¹; ¹University of Tsukuba, Institute of Mats. Sci., Tennodai 1-1-1, Tsukuba, Ibaraki 305-8573 Japan

Wednesday PM, June 30, 1999

Session H. Electronic Transport in Organic & Molecular Materials

Chairperson: Shelby Nelson, Colby College, Waterville, ME USA; David Janes, Purdue University, West Lafayette, IN USA

1:30 PM *Invited

What Determines the Resistance of a Molecule?: Supriyo Datta¹; ¹Purdue University, USA

2:10 PM

Simulation of Molecular Devices from First-Principal: *Massimiliano Di Ventra*¹; Norton Lang²; Sokrates T. Pantelides¹; ¹Vanderbilt University, Physics and Astronomy, Stevenson Center, Nashville, TN 37235 USA; ²IBM, Research Div., Thomas J. Watson Research Center, Yorktown Heights, New York, NY 10598 USA

2:30 PM +

Electronic Transport Characteristics Through Diisocyanide: *Jia Chen*¹; Laurie E. Calvet¹; Chongwu Zhou¹; Mark A. Reed¹; Dustin W. Carr²; Desiree S. Grubisha³; Dennis W. Bennett³; ¹Yale University, Electri. Eng. Dept., Rm. 509, 15 Prospect St., New Haven, CT 06520 USA; ²Cornell University, Cornell Nanofabrication Facility, G05 Knight Lab, Ithaca, NY 14853 USA; ³University of Wisconsin-Milwaukee, Dept. of Chem. and Biochem., 3210 North Cramer St., Milwaukee, WI 53211 USA

2:50 PM

Improved Contacts for Organic Electronic Devices Using Self-Assembled Charge Transfer Materials: *Jianna Wang*¹; David J. J. Gundlach¹; Chung-Chen Kuo¹; Thomas N. Jackson¹; ¹The Pennsylvania State University, Center for Thin Film Devices, and Electronic Mats. and Processing Research Laboratory, 121 EE East, University Park, PA 16802 USA

3:10 PM Break**3:30 PM *Invited**

High Mobility Charge Transportation Aromatic Hydrocarbon Single Crystals: *Jan Hendrik Schön*¹; Steffen Berg¹; Christian Kloc¹; Bertram Batlogg¹; ¹Bell Laboratories, Lucent Technologies, 700 Mountain Ave., Murray Hill, NJ 07974-0636 USA

4:10 PM

High Mobility Polymer Thin Film Transistors Based on Copolymers of Thiophene and 3-Hexyl Thiophene: *Jianna Wang*¹; David J. Gundlach¹; Alan J. Benesi²; Thomas N. Jackson¹; ¹The Pennsylvania State University, Center for Thin Film Devices, and Electr. Mats. and Processing Research Laboratory, 121 EE East, University Park, PA 16802 USA; ²The Pennsylvania State University, Chem. Dept., University Park, PA 16802 USA

4:30 PM +

Contact Limited Performance of Pentacene Thin Film Transistors: *David J. Gundlach*¹; Jonathan A. Nichols¹; Chung-Chen Kuo¹; Hagen Klauk¹; Chris D. Sheraw¹; Darrell G. Schlom²; Thomas N. Jackson¹; ¹The Pennsylvania State University, Dept. of Elect. Eng., 121 Elect. Eng. East, University Park, PA 16802 USA; ²The Pennsylvania State University, Dept. of Mats. Sci. and Eng., 103 Steidle Bldg., University Park, PA 16802-5005 USA

4:50 PM Late News

**Session I: Column IV
Heterostructures and Devices**

Session Chairs: Eugene Fitzgerald, MIT, Cambridge, MA USA; Ya-Hong Xie, UCLA, Dept. of Mats. Sci. & Eng., Los Angeles, CA USA

1:30 PM +

Exploitation of Facet Formations in SiGe/Si Selective Epitaxial Growth for Achieving a Nanometer Template: *Greg D. U'Ren*¹; Mark S. Goorsky¹; Kang L. Wang²; ¹UCLA, Dept. of Mats. Sci. and Eng., 6532 Boelter Hall, 405 Hilgard Ave., Los Angeles, CA 90095-1595 USA; ²UCLA, Dept. of Elect. Eng., 405 Hilgard Ave., Los Angeles, CA 90095-1594 USA

1:50 PM +

Selective Si Epitaxial Growth Using Ultrathin Oxide Mask Formed By Resistless Patterning: *Shawn G. Thomas*¹; Greg D. U'Ren²; Mark S. Goorsky²; Kang L. Wang¹; ¹University of California, Los Angeles, Elect. Eng. Dept., 63-109 Eng. IV, Los Angeles, CA 90095-1595; ²University of California, Los Angeles, Mats. Sci. and Eng. Dept., Los Angeles, CA 90095-1595

2:10 PM

Electrical and Structure Characterization of Single Crystalline SiGe Formed by Ge Deposition and RTP: *Y. H. Wu*¹; W. J. Chen²; Albert Chin¹; C. Tsai¹; ¹National Chiao Tung University, Dept. of Electronics Eng., Hsinchu, Taiwan ROC; ²National Huwei Inst. Tech., Dept. of Mechanical Mats. Eng., Huwei, Taiwan ROC

2:30 PM

Surfactant Mediated Epitaxy of Ge/Si Heterostructures for Device Applications: *Karl R. Hofmann*¹; Martin Kammmer¹; Dirk Reinking¹; Michael Horn-von Hoegen²; ¹University of Hannover, Inst. f. Halbleitertechnologie, Appelstrasse 11 A, D-30167 Hannover Germany; ²University of Hannover, Inst. F. Festkoerperphysik, Appelstrasse 2, D-30167 Hannover Germany

2:50 PM +

Direct Growth of Ge on Si for Integrated Si Microphotonic Photodetectors: *Hsin-Chiao Luan*¹; A. M. Agarwal¹; Kzumi Wada¹; E. A. Fitzgerald¹; L. C. Kimerling¹; ¹Massachusetts Institute of Tech., Dept. of Mats. Sci. and Eng., 13-4130, 77 Mass Ave., Cambridge, MA 02139 USA

3:10 PM Break

3:30 PM +

Boron Segregation in Polycrystalline Si(1-x-y)Ge(x)C(y) Alloys: *Eric Jonathan Stewart*¹; Malcolm S. Carroll¹; Chia-Lin Chang¹; James C. Sturm¹; ¹Princeton University, Dept. of Elect. Eng., Center

for Photonics and Optoelectronic Mats., J303 Eng. Quad, Olden St., Princeton, NJ 08544 USA

3:50 PM

X-ray Diffraction and Transmission Electron Microscopy Study of the Development of Texture in Polycrystalline $\text{Si}_{1-x}\text{Ge}_x$ Thin Films: *Wei Qin*¹; D. G. Ast²; T. I. Kamins³; ¹Institute of Microelectronics, 11 Sci. Park Rd., Singapore Sci. Park II, Singapore 117685 ROS; ²Cornell University, Mats. Sci. & Eng. Dept., Ithaca, NY 14853 USA; ³Hewlett-Packard Laboratories, Palo Alto 94303-0867 CA

4:10 PM

Diamond Epitaxy for Electronic Devices: *Aleksandar Aleksov*¹; Mike Kunze¹; Andrei Vescan¹; Wolfgang Ebert¹; Erhard Kohn¹; Andreas Bergmaier²; Guenther Dollinger²; ¹University of Ulm, Dept. of Electron Devices and Circuits, Albert-Einstein-Allee 45, Ulm D-89081 Germany; ²Technische Universitaet Muenchen, Dept. E12, Beschleunigerlabor der LMU/TUM, Muenchen Germany

4:30 PM +

Epitaxial Growth of Si/Y2O3/Si: A Potential SOS Structure: *Michael Edward Hunter*¹; Mason J. Reed¹; John C. Roberts²; N. A. El-Masry¹; S. M. Bedair²; ¹NC State University, Mats. Sci. and Eng., 232 Riddick Labs, P.O. Box 7916, Raleigh, NC 27695 USA; ²NC State University, Elect. and Comp. Eng., 232 Daniels Hall, P.O. Box 7911, Raleigh, NC 27695 USA

4:50 PM

In Situ Observation of Epitaxial Co Silicidation on Si(001): *Kunihiko Sakamoto*¹; Tatsuro Maeda¹; ¹Electrotechnical Laboratory, Electron Devices Div., 1-1-4 Umezono, Tsukuba, Ibaraki 305-8568 Japan

Thursday AM, July 1, 1999

Session J. Epitaxy for Devices

Session Chairs: Russell D. Dupris, University of Texas at Austin, PRO/MEP-R9900, Austin, TX USA; Steven Stockman, Hewlett-Packard Company, San Jose, CA USA

8:20 AM +

DC Characterization of Annealing Effect on the Carbon Doped Base of InGaP/GaAs HBTs Grown by LP-MOCVD: *Qinghong (Jack) Yang*¹; Dennis W. Scott¹; Patrick D. Meyer¹; John Miller¹; Gregory E. Stillman¹; ¹University of Illinois, Elect. and Comp. Eng., 208 N. Wright St., Urbana, IL 61801 USA

8:40 AM

Effect of High-Temperature Annealing on Device Performance of GaInP/GaAs HBTs Grown by LP-MOVPE: F. Brunner¹; E. Richter¹; T. Bergunde¹; *P. Kurpas*¹; A. Maasdorf¹; J. W. Tomm²; S. Gramlich¹; I. Rechenberg¹; S. Kraus¹; M. Achouche¹; J. Würfl¹; M. Weyers¹; ¹Ferdinand-Braun-Institut fuer Hoechstfrequenztechnik, Mats. Tech. Dept., Rudower Chaussee 5, D-12489 Berlin Germany; ²Max-Born-

9:00 AM

Low Resistance Visible Wavelength Distributed Bragg Reflectors: *J. M. Fastenau*¹; G. Y. Robinson¹; ¹Colorado State University, Dept. of Elect. & Comp. Eng., Fort Collins, CO 80523 USA

9:20 AM

High P-Type Doping in InAlP Grown by Metalorganic Chemical Vapor Deposition: *Yuichi Sasajima*¹; Russell D. Dupuis¹; ¹The University of Texas at Austin, Microelectronics Research Center, PRC/MER 2.606K-R9950, Austin, TX 78712-1100 USA

9:40 AM +

Growth and Characterization of InAlGaP Superlattice Lasers: *Yuichi Sasajima*¹; *Richard D. Heller*¹; Russell D. Dupuis¹; David A. Kellogg²; Nick Holonyak²; David T. Mathes³; Robert Hull³; ¹The University of Texas at Austin, Microelectronics Research Center, PRC/MER 1.606D, Austin, TX 78712-1100 USA; ²University of Illinois at Urbana-Champaign, Microelectronics Laboratory, 208 North Wright St., Urbana, IL 68101-2991 USA; ³University of Virginia, Dept. of Mats. Sci. and Eng., Thornton Hall, Charlottesville, VA 22903-2442 USA

10:00 AM Break

10:20 AM

Device Quality, Bandgap Engineered InAs-Channel FET Material Structures: *Leye A. Aina*¹; Harry S. Hier¹; Anu Mahajan²; G. Cueva²; Ilesanmi Adesida²; Terrance L. Worchesky³; Rheanna Riebau³; ¹Epitaxial Technologies, LLC, 1450 South Rolling Rd., Baltimore, MD 21227 USA; ²University of Illinois Urbana Campus, 208 North Wright St., Urbana, IL 61801 USA; ³University of Maryland Baltimore County, 1000 Hilltop Circle, Baltimore, MD 21250 USA

10:40 AM

Transport Properties of InAs Layers Grown on GaP Substrate by MBE: *E. H. Chen*¹; V. Gopal²; E. P. Kvam²; J. M. Woodall¹; ¹Yale University, Dept. of Elect. Eng., New Haven, CT 06520; ²Purdue University, School of Mats. Eng., W. Lafayette, IN 47907

11:00 AM

Effects of HEMT Pseudomorphic Channel Material Design on Device Performance: *Yaochung Chen*¹; Richard Lai¹; Mike Wojtowicz¹; Mike Barsky¹; Ronald Grundbacher¹; T. P. Chin¹; Dwight C. Streit¹; ¹TRW, Inc., Electr. & Tech. Div., One Space Park, D1/1050, Redondo Beach, CA 90278 USA

11:20 AM

Growth of High-Performance InP IMPATT Diodes by Metalorganic Chemical Vapor Deposition: *Ho-Ki Kwon*¹; Joongseo Park¹; Russell D. Dupuis¹; James W. McClymonds²; Michael J. Welch²; ¹The University of Texas at Austin, Microelectronics Research Center, MRC/MER - R9900, Austin, TX 78712-1100 USA; ²Raytheon Electronic Systems, 131 Spring St., Lexington, MA 02173 USA

11:40 AM Late News

Session K. Nanoscale Characterization

Session Chairs: Julia Hsu, University of Virginia, Charlottesville, VA USA; Edward Yu, University of California, San Diego, CA USA

8:20 AM +

Nanoscale Charge Transport Properties of Co/SiO₂ Multilayer Structures and Their Application in a Novel Magnetic Field Sensor: *Daniel M. Schaadt*¹; Edward T. Yu¹; Sandra Sankar²; Ami E. Berkowitz²; ¹University of California at San Diego, Dept. of Elect. and Comp. Eng., 9500 Gilman Drive, La Jolla, CA 92093-0407 USA; ²University of California at San Diego, Dept. of Phys., Center for Magnetic Recording Research, 9500 Gilman Dr., La Jolla, CA 92093-0401 USA

8:40 AM

Novel Application of Kelvin Force Microscopy: *Rafi Shikler*¹; Tamir Meoded¹; Norbert Fried¹; Nurit Ashkenasy¹; Yossi Rosenwaks¹; ¹Tel-Aviv University, Faculty of Electr. Eng., Dept. of Phy. Electr., Ramat-Aviv, Tel-Aviv 69978 Israel

9:00 AM +

InGaAs/InP Quantum Well Intermixing Studied by Cross-Sectional Scanning Tunneling Microscopy: *Huajie Chen*¹; Randall M. Feenstra¹; P. G. Piva²; I. V. Mitchell²; R. D. Goldberg³; G. C. Aers⁴; P. J. Poole⁴; S. Charbonneau⁴; ¹Carnegie Mellon University, Dept. of Phys., Pittsburgh, PA 15213; ²University of Western Ontario, Dept. of Phys. and Astronomy, London N6A3k7 Canada; ³University of Salford, Joule Laboratory, Dept. of Phys., Salford M5 4WT UK; ⁴National Research Council of Canada, Institute for Microstructural Sciences, Ottawa K1A0R6 Canada

9:20 AM

Role of Interface Roughness in High-Electron Mobility Transistor (HEMT) Structures: An MBE-STM Study: *Haeyeon Yang*¹; Zhao Ding¹; Daniel B. Bullock¹; Vincent P. LaBella¹; Paul M. Thibado¹; ¹University of Arkansas, Dept. of Phys., Fayetteville, AR 72701

9:40 AM

Ordering-Induced Band Structure Effects in GaInP Studied by Ballistic Electron Emission Spectroscopy: *Michael Kozhevnikov*¹; Venkatesh Narayanamurthy¹; Yong Zhang²; Angelo Mascarenhas²; Jerry Olson²; ¹Harvard University, Gordon McKay Laboratory, 9 Oxford St., Cambridge, MA 02138 USA; ²National Renewable Energy Laboratory, 1617 Cole Boulevard, Golden, CO 80401 USA

10:00 AM Break

10:20 AM +

Nanoscale Characterization of Stresses in Semiconductor Devices: *James John Demarest*¹; Robert Hull¹; Kathryn Schonenberg²; Koenraad Janssens³; ¹University of Virginia, Mats. Sci. and Eng., Thornton Hall, McCormick Rd., Charlottesville, VA 22903 USA; ²International Business Machines Corporation, IBM Research Div./SRDC,

Hudson Valley Research Park, 1580 Rt. 52, B/640, M/S AE1, Hopewell Junction, NY 12533 USA; ³OCAS, The Research Centre of the Sidmar Group, J.F. Kennedylaan 3, B-9060, Zelzate Belgium

10:40 AM

Extending Lateral Composition Modulations in InAs/AlAs Superlattices with Miscut Substrates: *David M. Follstaedt*¹; Andrew G. Norman²; S. Phil Ahrenkiel²; John L. Reno¹; Steve R. Lee¹; Eric D. Jones¹; Joanna Mirecki Millunchick³; Angelo Mascarenhas²; Yong Zhang²; Ray D. Twisten⁴; ¹Sandia National Laboratories, Dept. 1112, Mail Stop 1056, Albuquerque, NM 87185-1056 USA; ²National Renewable Energy Laboratory, Golden, CO 80401-2163 USA; ³University of Michigan, Mats. Sci. and Eng., Ann Arbor, MI 48109-2163 USA; ⁴University of Illinois, Center for Microanalysis, Urbana, IL 61801-2985 USA

11:00 AM +

Non-Alloyed Ohmic Contact on GaAs at Nanometer Scale: *Takhee Lee*¹; B. L. Walsh³; D. B. Janes³; E. H. Chen³; Jia Liu²; J. M. Woodall³; M. R. Melloch³; R. P. Andres²; R. Reifengerger¹; ¹Purdue University, Dept. of Phys., W. Lafayette, IN 47907 USA; ²Purdue University, School of Chemical Eng., W. Lafayette, IN 47907; ³Purdue University, School of Elect. and Comp. Eng., W. Lafayette, IN 47907

11:20 AM

Nanomagnetic and Superconducting Properties of Self-Assembled Quantum Dots: *Supriyo Bandyopadhyay*¹; Latika Menon¹; Seema Nair¹; Hou Zheng²; David J. Sellmyer²; ¹University of Nebraska, Dept. of Elect. Eng., Lincoln, Nebraska 68588-0511 USA; ²University of Nebraska, Dept. of Phys., Lincoln, NE 68588-0111 USA

11:40 AM Late News

Thursday AM, July 1, 1999

**Session L. Wide Bandgap
AlGaIn/GaN Heterostructures**

Session Chairs: Ilesanmi Adesida, University of Illinois-Urbana, Urbana-Champaign, IL USA; Umesh Mishra, University of California, ECE Dept., Santa Barbara, CA USA

8:20 AM

Stress/Strain during MOCVD of AlGaIn/GaN on LT GaN/AlN Buffers: *Jung Han*¹; Jeff J. Figiel¹; Sean J. Hearne¹; Jerry A. Floro¹; Steve R Lee¹; ¹Sandia National Laboratories, MS-0601, P.O. Box 5800, Albuquerque, NM 87185-0601 USA

8:40 AM +

Local Electronic Structure of AlGaIn/GaN Heterostructures Probed by Scanning Capacitance Microscopy: *Kurt V. Smith*¹; Ed T. Yu¹; J. M. Redwing²; K. S. Boutros²; ¹University of California, San

Diego, Elect. and Comp. Eng., 9500 Gilman Dr. 0407, La Jolla, CA 92093 USA; ²ATMI/Epitronics

9:00 AM

Polarization Fields in AlGaIn/GaN Heterojunctions: *James Paul Ibbetson*¹; ¹University of California, ECE Dept., Santa Barbara, CA 93106

9:20 AM +

Surface Potential Effects Due to the Piezoelectric Charge Associated with Dislocations in GaN: *Changchun Shi*¹; Peter M. Asbeck²; Edward T. Yu²; ¹University of California, San Diego, Dept. of Phys., 9138-I, Regents Rd., La Jolla, CA 92037; ²University of California, San Diego, Dept. of Elect. and Comp. Eng., San Diego, CA

9:40 AM

Two Dimensional Electron Gas Density and Polarization Effects in AlGaInN/GaN Heterostructures: *J. W. Yang*¹; Asif Khan¹; R. Gaska²; G. Simin¹; A. Bykhovski²; Michael S. Shur²; ¹University of South Carolina, ECE Dept., Columbia, SC 29208 USA; ²Rensselaer Polytechnic Institute, ECSE and CIEEM, Troy, NY 12180 USA

10:00 AM Break

10:20 AM +

Growth and Characterization of AlGaIn/GaN Heterostructures: *Christopher J. Eiting*¹; Damien J. H. Lambert¹; Ho-Ki Kwon¹; Bryan S. Shelton¹; Mike M. Wong¹; Ting-Gang Zhu¹; Doris E. Lin¹; Russell D. Dupuis¹; ¹The University of Texas at Austin, PRC/MER-R9900, Microelectronics Research Center, Austin, TX 78712-1100 USA

10:40 AM

Effect of Surface Roughness on Electron Mobility in AlGaIn/GaN Heterostructures.: *Asif Khan*¹; Remis Gaska²; J. W. Yang¹; Michael S. Shur²; ¹USC, ECE, Columbia, SC 29208 USA; ²Rensselaer Polytechnic Institute, ECSE and CIEEM, Troy, NY 12180 USA

11:00 AM +

High Electron Mobility 2DEG in AlGaIn/GaN Structures: *Chris R. Elsass*¹; Yulia Smorchkova²; Erik Haus¹; Paul Fini¹; Pierre Petroff³; Steven P. DenBaars³; Umesh Mishra²; James Speck¹; Ben Heying¹; ¹University of California, Santa Barbara, Mats. Dept., Santa Barbara, CA 93106 USA; ²University of California, Santa Barbara, ECE, Santa Barbara, CA 93106; ³University of California, Santa Barbara, Mats. and ECE Dept., Santa Barbara, CA 93106

11:20 AM

Correlation Between Material Quality and Low-Frequency Noise Level in GaN Heterostructure Field Effect Transistors: *Alexander A. Balandin*¹; Richard Li¹; Shujun Cai¹; Jiang Li¹; Kang L. Wang¹; E. N. Wang²; M. Wojtovicz²; ¹UCLA, Elect. Eng. Dept., Device Research Laboratory, Rm. 56-125B, Eng. IV Bldg., UCLA, Los Angeles, CA 90095 USA; ²TRW Inc., Redondo Beach, CA 90278 USA

11:40 AM

Characterization of GaN MIS Structures: *Tamotsu Hashizume*¹; Ryuusuke Nakasaki¹; Hideki Hasegawa¹; ¹Research Center for Interface Quantum Electronics (RCIQE) and Graduate School of Electronics and Information Eng., Hokkaido University, Kita-ku, Kita 13 Nishi 8, Sapporo, Hokkaido 060-8628 Japan

Session M. SiC Growth & Characterization

Session Chairs: Marea Skowronsici, Carnegie Mellon University, Pittsburgh, PA USA; Shigehiro Nishino, Kyoto Institute of Technology, Kyoto, Japan

8:20 AM +

Formation of Macrodefects in SiC Physical Vapor Transport Growth: *Edward Kyle Sanchez*¹; Volker D. Heydemann²; Tom Kuhr¹; Gregory S. Rohrer¹; Marek Skowronski¹; ¹Carnegie Mellon University, Mats. Sci. and Eng., 5000 Forbes Ave., 138 Roberts Hall, Pittsburgh, PA 15213 USA; ²II-VI Inc., 375 Saxonburg Blvd., Saxonburg, PA 16056 USA

8:40 AM

Local Epitaxy and Epitaxial Lateral Overgrowth of SiC: *Igor Ivanovich Khlebnikov*¹; Yuri Igorevich Khlebnikov¹; J. A. Freitas²; Tangali S. Sudarshan¹; ¹University of South Carolina, Dept. of Elect. & Comp. Eng., 301 S. Main St., Columbia, SC 29208 USA; ²Naval Research Laboratory, Electronics Sci. and Tech. Div., 4555 Overlook Ave., S.W., Washington, DC 20375-5347 USA

9:00 AM

Susceptor Effects on 4H-SiC Epitaxial Growth: *Barbara E. Landini*¹; ¹ATMI, 7 Commerce Drive, Danbury, CT 06810 USA

9:20 AM

Epitaxial Growth of 6H-SiC on Spherically Polished 6H-SiC Substrate Using Si₂Cl₆+C₃H₈ +H₂ by CVD: *Shigehiro Nishino*¹; Yasuichi Masuda¹; Yuki Nishio¹; ¹Dept. of Electronics and Information Sci., Faculty of Eng. and Design, Kyoto Institute of Tech., Matsugasaki, Sakyo-ku, Kyoto 606 Japan

9:40 AM +

Crystalline Quality and Polytype Formation of SiC Films Grown With Different Concentrations of Ge on (111) Si Substrates: *Wendy L. Sarney*¹; Lourdes G. Salamanca-Riba¹; P. Zhou²; Crawford Taylor²; Michael Spencer²; R. P. Sharma¹; K. A. Jones³; ¹University of Maryland, College Park, Dept. Mats. & Nuclear Eng., Bldg. 090, College Park, MD 20742 USA; ²Howard University, Mats. Sci. Center of Excellence, 2300 6th St. NW, Washington, DC 20059 USA; ³U.S. Army Research Lab, Adelphi, MD 20783 USA

10:00 AM Break

10:20 AM

Deep Donor in Bulk N-Type 4H-SiC: *W. C. Mitchel*¹; A. Saxler¹; Ronald E. Perrin¹; John Sizelove¹; S. R. Smith¹; J. S. Solomon¹; A. O. Evwaraye²; ¹Air Force Research Laboratory, Mats. and Manufacturing Div., AFRL/MLP, Wright-Patterson AFB, OH 45433-7707 USA; ²University of Dayton, Dept. of Phys., 3000 College Park, Dayton, OH 45469 USA

10:40 AM +

Radiotracer Spectroscopy on Ta Related Deep Levels in 4H-SiC:

*Joachim Kurt Grillenberger*¹; Norbert Achtziger¹; Rainer Sielemann²;
¹University of Jena, Institut für Festkörperphysik, Max-Wien-Platz 1,
Jena 07743 Germany; ²Hahn-Meitner-Institut, FD, Glienicker Straße
100, Berlin 14109 Germany

11:00 AM

Effect of NO Annealing Conditions on Electrical Characterization of N-Type 4H-SiC MOS Capacitors:

*Hui-feng Li*¹; Denis Sweatman¹; Sima Dimitrijević¹; H. Barry Harrison¹; ¹Griffith University,
School of Microelectronic Eng., Brisbane, QLD 4111 Australia

11:20 AM Late News

11:40 AM Late News

Thursday AM, July 1, 1999

Session N. Infrared Materials and Devices

Session Chairs: Robert M. Biefeld, Sandia National
Laboratory, Dept. 1113, Albuquerque, NM USA; Tom
Bogges, University of Iowa, Iowa City, IA USA

8:20 AM

Influence of Interfacial Layers on GaAsSb/InP Heterostructures:

Xiangang Xu¹; Jinsheng Hu¹; Nouredine Matine¹; *Simon P. Watkins*¹;
Colombo R. Bolognesi¹; ¹Simon Fraser University, Dept. of Phys.,
8888 University Dr., Burnaby, BC V5A 1S6 Canada

8:40 AM

MOCVD Growth of InAsSb/InPSb SLS's for Use in Infrared Emitters:

*Robert M. Biefeld*¹; Steven R. Kurtz¹; Jamie D. Phillips¹;
¹Sandia National Laboratory, 1113, MS 0601, P.O. Box 5800, Albuquerque,
NM 87185-0601 USA

9:00 AM +

MBE Growth of High Quality InGaAsSb/AlGaAsSb Heterostructures Using the Digital Alloying Technique:

*C. Mourad*¹; K. J. Malloy¹; R. Kaspi²; ¹Center for High Tech. Mats., University of New
Mexico, Albuquerque 87106 NM; ²Air Force Research Laboratory,
AFRL/DELS, Kirtland, AFB 87117

9:20 AM

InSb Based Mid-IR Light Emitting Diodes and Lasers:

*Tim Ashley*¹; David T. Dutton¹; C. Tom Elliott¹; Neil T. Gordon¹; Andrew D. Johnson¹;
Tim J. Phillips¹; Graham J. Pryce¹; Graham Berry²; Ben N. Murdin³;
Eoin P. O'Reilly³; ¹Defence Evaluation & Research Agency, St. Andrews
Rd., Malvern, Worcestershire WR14 3PS UK; ²University of Wales,
Cardiff, Dept. of Phys. & Astro., P.O. Box 913, Cardiff, Wales CF2
3YB UK; ³University of Surrey, Dept. of Phys., Guildford, Surrey GU2
5XH UK

9:40 AM

New Techniques for EPI-Down Mounting of Mid-IR Type-II Quantum-Well Lasers: *Edward Hugh Aifer*¹; William W. Bewley¹; Christopher L. Felix¹; Linda J. Olafsen¹; Igor Vurgaftman¹; Donna W. Stokes¹; Jerry R. Meyer¹; ¹Naval Research Laboratory, Optical Sciences, Code 5613, 4555 Overlook Ave., Washington, DC 20375 USA

10:00 AM Break

10:20 AM

Linewidth Enhancement Factor in Mid-Infrared Semiconductor Laser Active Regions: *Michael E. Flatte*¹; J. T. Olesberg¹; Thomas F. Boggess¹; ¹The University of Iowa, Dept. of Phys. and Astronomy, 100 IATL, Iowa City, IA 52242 USA

10:40 AM +

Carrier Recombination Dynamics of InGaSb Under Picosecond Free-Electron Laser Excitation: *R. T. Kotitschke*¹; A. R. Adams¹; B. N. Murdin¹; H. Pellemans²; T. Ashley³; G. Pryce³; A. D. Johnson³; C. T. Elliott³; P. C. Findlay⁴; C. R. Pidgeon⁴; ¹University of Surrey, Dept. of Phys., Guildford, Surrey GU2 5XH UK; ²FOM Institute for Plasma Physics, "Rijnhuizen", P.O. Box 1207, Nieuwegein 3430 BE The Netherlands; ³DERA, St. Andrews Rd., Malvern, Worcs. WR14 3PS UK; ⁴Heriot-Watt University, Dept. of Phys., Edinburgh EH14 4AS UK

11:00 AM

Optical and Structural Studies of InAsSb/AlInAsSb Quantum Wells for Use in MID-IR Lasers: *Philip D. J. Calcott*¹; Trevor Martin¹; Martin T. Emeny¹; Michael J. Kane¹; David J. Wallis¹; Gerald Williams¹; ¹Dera Malvern, Electronics Div., St. Andrews Rd., Great Malvern, Malvern, Worcs. WR14 3PS UK

11:20 AM

Fabrication of a 3-D Simple Cubic Infrared Photonic Crystal: *Lisa Zavieh*¹; Theresa S. Mayer²; ¹The Pennsylvania State University, Intercollege Mats. Eng. Program, 121 Elect. Eng. East, University Park, PA 16802 USA; ²Penn State University, Dept. of Elect. Eng., 121 Elect. Eng. East, University Park, PA 16802 USA

11:40 AM

In_xGa_{1-x}As/Al_yGa_{1-y}As/Al_zGa_{1-z}As Asymmetric Step Quantum Well Mid-Infrared (3-5.3 μ m) Detectors: *Wen-Gang Wu*¹; ¹University of California, Los Angeles, Device Research Lab., Elect. Eng. Dept., 56-125B EIV, Box 951594, Los Angeles, CA 90095-1594 USA

**Session O. Issues for Ferroelectric
and High Permittivity Thin Film Materials**

Session Chairs: Laura Wills, Hewlett Packard Laboratories, Palo Alto, CA USA; Paul McIntyre, Stanford University, Dept. of Mats. Sci. & Eng., Stanford, CA USA

8:20 AM *Invited

Modeling of Oxide Materials for Memory Applications: *Rainer Waser*¹; ¹IFF, Research Center, Julich D-52425 Germany

9:00 AM

The Effect of Thickness on the Dielectric Properties of Thin Epitaxial Films of BaTiO₃: *Soma Chattopadhyay*¹; Andrew Teren¹; Brent H. Hoerman¹; Jin-Ha Hwang¹; Thomas O. Mason¹; Bruce W. Wessels¹; ¹Northwestern University, Mats. Sci. & Eng. Dept., Mats. Sci. and Life Sciences Bldg., 2225 N. Campus Dr., Evanston, IL 60208 USA

9:20 AM

Non-Stoichiometry Accommodation and Properties in (BaxSr1-x)Ti1+yO3+z Thin Films Grown By Chemical Vapor Deposition: *Susanne Stemmer*¹; Stephen K. Streiffer²; Nigel D. Browning¹; C. B. Parker³; Angus I. Kingon³; ¹University of Illinois at Chicago, Phys. Dept., 845 W. Taylor St., Chicago, IL 60607-7059 USA; ²Argonne National Laboratory, Mats. Sci. Div., 9700 South Cass Ave., Bldg. 212, Argonne, IL 60439-4838 USA; ³North Carolina State University, Dept. Mats. Sci. and Eng., Raleigh, NC 27695-7919 USA

9:40 AM

A Mass Spectral Study of the Surface Decomposition Chemistry of Precursors for Chemical Beam Epitaxy of Lithium Niobate: *Dovas Saulys*¹; Vladimir Joshkin²; Mikhail Khoudiakov¹; Arthur Ellis¹; Thomas F. Kuech³; Leon McCaughan⁴; ¹University of Wisconsin, Dept. of Chem., Room 7303, 1101 University Ave., Madison, WI 53706 USA; ²University of Wisconsin, Mats. Research Sci. & Eng. Ctr., Room 1111, 1415 Eng. Dr., Madison, WI 53706 USA; ³University of Wisconsin, Dept. of Chem. Eng., 1410 Eng. Dr., Madison, WI 53706 USA; ⁴University of Wisconsin, Dept. of Elect. & Comp. Eng., 1415 Eng. Dr., Madison, WI 53706 USA

10:00 AM Break

10:20 AM *Invited

Advanced Gate Dielectrics for Scaled CMOS: *Glen Wilk*¹; ¹Texas Instruments, Central Research Labs, Dallas, TX 75243

11:00 AM

Characterization of MFIS and MFMIS Structures Using SrBi₂Ta₂O₉ Film with SrTa₂O₆/SiON Stacked Buffer Layer: *Eisuke Tokumitsu*¹; Gen Fujii²; Hiroshi Ishiwara²; ¹Tokyo Institute of Technology, Precision and Intelligence Lab., 4259 Nagatsuta, Midori-ku, Yokohama, Kanagawa 226-8503 Japan; ²Tokyo Institute of Technology, Frontier Collaborative Res. Center, 4259 Nagatsuta, Midori-ku, Yokohama, Kanagawa 226-8503 Japan

11:20 AM

Process Integration of TEOS-Based SiO₂ Films for Inter-Layer Dielectric on Ferroelectric Capacitors: Jeong-han Kim¹; *Yang-han Yoon*¹; Heon-Do Kim¹; Sam-Dong Kim¹; Jeong-Tae Kim¹; ¹Hyundai Electronics Industries, Co., Ltd., Semiconductor Advanced Research Div./Process Research Dept. IV, 633, Sinhae-ri, Ganam-myun, Yeju-kun, Kyoungki-do 467-880 Korea

11:40 AM

Photo-Patternable Precursors to Oxide Electrodes for Ferroelectric Memory Devices: *Charles D. E. Lakeman*¹; Adam C. King¹; ¹TPL Inc., Specialty Mats., 3921 Academy Parkway North, NE, Albuquerque, NM 87109 USA

Thursday PM, July 1, 1999

Session P. Ordering in Semiconductor Alloys

Session Chairs: Alex Zunger, NREL, Golden, CO USA; Gerald Stringfellow, University of Utah, College of Eng., Salt Lake City, UT USA

1:30 PM

Ordered InGaAs: Low-Temperature MOVPE Growth and Polarization Dependent Electroabsorption Measurements: *Werner Prost*¹; Jochen Spieler²; Peter Velling¹; Thomas Kippenberg²; Peter Kiesel²; Jan Krauss²; Gottfried H. Dohler²; F. J. Tegude¹; ¹Gerhard-Mercator-University Duisburg, Solid-State Electronics Dept., Lotharstraße 65, ZHO, Gebäude LT, Duisburg D-47057 Germany; ²Friedrich-Alexander University Erlangen-Nürnberg, Institute for Technical Physics I, Erwin-Rommel-Str. 1, Erlangen D-91058 Germany

1:50 PM

Microstructure of CuPt-B Ordered GaInAs Films: *S. P. Ahrenkiel*¹; D. J. Arent¹; M. C. Hanna¹; ¹National Renewable Energy Laboratory, 1617 Cole Blvd., Golden, CO 80401 USA

2:10 PM

Phase Separation and Ordering Co-Existing in MOCVD In_xGa_{1-x}N: *Mark K. Behbehani*¹; Edwin L. Piner¹; Sandra X. Liu¹; Nadia A. El-Masry¹; Salah M. Bedair²; ¹North Carolina State University, Mats. Sci. and Eng., 232 Riddick, P.O. Box 7916, Raleigh, NC 27695 USA; ²North Carolina State University, Elect. and Comp. Eng., 432 Daniels, P.O. Box 7911, Raleigh, NC 27695 USA

2:30 PM

Band Structure and Stability of Ordered Zinc-Blende-Based Semiconductor Polytypes: *Su-Huai Wei*¹; A. Zunger¹; S. B. Zhang¹; Tomi Mattila¹; ¹National Renewable Energy Laboratory, 1617 Cole Blvd., Golden, CO 80401 USA

2:50 PM

X-ray Diffraction Study of Ordering in Epitaxial ZnSnP₂: *Sebastien Francoeur*¹; G. A. Seryogin¹; S. A. Nikishin¹; H. Temkin¹; ¹Texas Tech University, Elect. Eng. Dept., Lubbock, TX 79409 USA

3:10 PM Break

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Comparison of Dopants Used to Control Ordering in GaInP: *Chris Fetzer*¹; Yu Hsu¹; Rung-Ting Lee¹; Sung-Won Jun¹; J. Kevin Shurtleff¹; Gerald B. Stringfellow¹; ¹University of Utah, Dept. of Mats. Sci. and Eng., 223 KRC, Salt Lake City, UT 84112 USA

3:50 PM

Ordering and Antiphase Boundaries in Te-Doped GaInP Layers Grown by Organometallic Vapour Phase Epitaxy: *T-Y Seong*¹; C.-J. Choi¹; S.H. Lee²; G.B. Stringfellow²; ¹Kwangju Institute of Sci. and Tech., Dept. of Mats. Sci. and Eng., Kwangju 500-712 Korea; ²University of Utah, Dept. of Mats. Sci. and Eng., Salt Lake City, UT 84112 USA

4:10 PM

Maximum Direct-Gap Reduction in CuPt Ordered $Al_xGa_{1-x}InP$ ($0 \leq x \leq 1$) Determined by Generalized Ellipsometry: *M. Schubert*¹; J. A. Woollam¹; B. Rheinlander²; I. Pietzonka³; V. Gottschalch³; ¹University of Nebraska-Lincoln, Center for Microelectronic and Optical Mats. Research, Lincoln, NE 68588; ²University Leipzig, Faculty of Physics and GeoSci., Leipzig 04103 Germany; ³University Leipzig, Faculty of Chem. and Min. Ogy, Leipzig 04103 Germany

4:30 PM

A Polarized-Piezoreflectance Study of Spontaneous Ordering in AlInP₂ Including the Effects of Temperature: *W. C. Yeh*¹; *Ying-sheng Huang*¹; C. S. Chang²; ¹National Taiwan University of Sci. and Tech., Dept. of Electr. Eng., 43 Keelung Rd. Sec. 4, Taipei 106 Taiwan; ²United Epitaxy Company, Hsinchu 300 Taiwan

4:50 PM +

Observation of Type I/II Transition in GaAs/InGaP Heterostructure by C-V Profiling: *Shouvik Datta*¹; M. R. Gokhle¹; A. P. Shah¹; T. K. Sharma²; B. M. Arora¹; ¹Tata Institute of Fundamental Research., Solid State Electronics Group/Dept. of Condensed Matter Phys. & Mats. Sci., Homi Bhabha Rd., Colaba, Mumbai, Maharashtra. 400 005. India; ²Centre for Advance Tech., Indore 452 013 India

Thursday PM, July 1, 1999

Session Q. Nanostructure Self-Assembly

Session Chairs: Supriyo Bandyopadhyay, University of Nebraska, Dept. of Elect. Eng., Lincoln, NE USA; David Janes, Purdue University, School of Elect. Eng., West Lafayette, IN USA

1:30 PM

In-Situ Growth of InAs Quantum Dots on Patterned GaInAs/InP Nanostructures: Magnus Borgström²; Jonas Johansson¹; Ivan Maximov¹; *Werner Seifert*¹; Lars Samuelson¹; ¹University of Lund, Solid State Phys., Box 118, Lund S-221 00 Sweden

1:50 PM

Formation of Nanoscale Self-Assembled Si_{1-x}Ge_x Islands Using Chemical Vapor Deposition and Subsequent Thermal Annealing of Thin Metastable Films: *Rashid Bashir*¹; Abul Ehsan Kabir²; Kuo-Jen Chao³; Cara L. Weitzsacker³; ¹Purdue University, Elect. and Comp Engr, 1285 EE Bldg., W. Lafayette, IN 47906 USA; ²National Semiconductor, 2900 Semiconductor Dr., MS E-100, Santa Clara, CA 95051 USA; ³Charles Evans and Associates, 240 Santa Ana Court, Sunnyvale, CA 94086 USA

2:10 PM +

Fabrication and Characterization of Magnetic Semiconductors “Spin Wires” and “Spin Dots”: *O. Ray*¹; J. J. Berry¹; A. A. Sirenko¹; N. Samarth¹; J. A. Gupta²; I. Malajovich²; D. D. Awschalom²; ¹Pennsylvania State University, Dept. of Phys., 104 Davey Lab, State College, PA 16802 USA; ²University of California, Dept. of Phys., Santa Barbara, CA 93106

2:30 PM

Preparation and Characterization of Gold-Platinum Nanorods: Sa Huang¹; Benjamin Martin²; Daniel Dermody²; Thomas Mallouk²; Thomas Jackson¹; *Theresa Mayer*¹; ¹Penn State University, Elect. Eng., 121 Elect. Eng. East, University Park, PA 16802 USA; ²Penn State University, Dept. of Chemistry

2:50 PM +

Self-Assembly of Patterned Films of Nanometer-Diameter Gold Clusters that are Linked by Organic Molecules: *Jia Liu*¹; Ronald P. Andres¹; ¹Purdue University, Dept. of Chem. Eng., 1283 Chem. Eng. Bldg., West Lafayette, IN 47907-1283 USA

3:10 PM Break**3:30 PM +**

Directed Self-Assembly of Metal/Semiconductor Structures for Nanoelectronic Devices and Circuits: *Brian L. Walsh*¹; M. Batistuta¹; Takhee Lee²; Jia Liu³; Q. Qu³; E. H. Chen¹; R. P. Andres¹; D. B. Janes¹; R. Reifenger²; ¹Purdue University, School of Elect. and Comp. Eng., West Lafayette, IN 47907; ²Purdue University, Dept. of Phys., Lafayette, IN 47907; ³Purdue University, School of Chem. Eng., West Lafayette, IN 47907

3:50 PM

Dry-Etched Grating in the MQW Active Layer for DFB Laser Arrays Fabrication: *Talneau Anne*¹; Bouadma Nouredine¹; Slemkpes Serge¹; Ougazzaden Abdallah¹; ¹OPTO+, France Telecom/CNET, Route de Nozay, Marcoussis 91460 France

4:10 PM

Various AFM Nano-Oxidation Processes for Planar Type Single Electron Transistor: *K. Matsumoto*¹; Y. Gotoh¹; T. Maeda¹; ¹Electrotechnical Laboratory, 1-1-4, Umezono, Tsukuba-shi, Ibaraki-kenn, 305 Japan

4:30 PM +

Semiconductor Patterning Techniques Based on Self-Assembled Structures: *M. V. Batistuta*¹; D. B. Janes¹; B. Walsh¹; J. Liu¹; Q. Qu¹; R. P. Andres¹; E. L. Peckham¹; E. -H. Chen¹; ¹Purdue University

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Thermo-Mechanical Properties of Polymers for Nanoimprint Lithography: *Thomas Hoffmann*¹; Frank Gottschalch¹; Clivia M. Sotomayor Torres¹; ¹BUGH Wuppertal, Institute of Mats. Sci., Gauss-Str. 20, Wuppertal 42097 Germany

Thursday PM, July 1, 1999

Session R. Properties of InGaN Heterostructures and Devices

Session Chairs: Joan Redwing, Epitronics, Phoenix, AZ USA; Christian Wetzel, Meijo University, High Tech Research Center 1-501, Shigomaguchi Tenpaku-ku, Nagoya, Japan

1:30 PM

Single-Mode Nitride-Based Laser Diodes Using Thick n-AlGaIn Layers: *T. Takeuchi*¹; N. Hayashi¹; M. Iwaya¹; K. Isomura¹; K. Kimura¹; M. Yamaguchi¹; T. Detchprohm¹; S. Yamaguchi¹; C. Wetzel¹; H. Amano¹; I. Akasaki¹; S. Watanabe²; Y. Yamaoka²; R. Shioda²; T. Hidaka²; Ys. Kaneko²; Yw. Kaneko²; N. Yamada²; ¹Dept. of Elect. and Electr. Eng., Meijo University, Nagoya 468-8502 Japan; ²Hewlett-Packard Laboratories, 3-2-2 Sakado, Takatsu-ku, Kawasaki 213-0012 Japan

1:50 PM

Violet-Blue InGaIn/GaN MQW Light Emitting Diodes on Epitaxially Laterally Overgrown GaN: *Koen Jacobs*¹; Wim Van der Stricht¹; Ingrid Moerman¹; Piet Demeester¹; Steven Verstuyft¹; Joël De Nayer¹; Peter Van Daele¹; Amal Amokrane²; Sophie Dassonneville²; Brigitte Sieber²; Edward J. Thrush³; ¹University of Gent, Inform. Tech.-IMEC, Sint-Pietersnieuwstraat 41, Gent B-9000 Belgium; ²Université des Sciences et Technologies de Lille, Laboratoire de Structure et Propriétés de l'Etat Solide, UPRESA 8008, Bâtiment C6, Villeneuve d'Ascq Cédex 59655 France; ³Thomas Swan & Co, Ltd., Unit 1C, Button End, Harston, Cambridge CB2 5NX UK

2:10 PM

Dislocation Reduction in GaN Epilayers via Lateral Overgrowth from Trenches: *Y Chen*¹; S.Y. Wang¹; R. S. Kern²; C. H. Chen²; C. P. Kuo²; ¹Hewlett-Packard Company, Hewlett-Packard Laboratories, 3500 Deer Creek Rd. MS26U-12, Palo Alto, CA 94304; ²Hewlett-Packard Company, Optoelectronics Div., 370 West Trimble Rd., San Jose, CA 95131

2:30 PM +

Measurement of Crystallographic Tilt in the Lateral Epitaxial Overgrowth of GaN: *Paul T. Fini*¹; James P. Ibbetson²; Hugues Marchand²; Lijie Zhao¹; Steven P. DenBaars¹; James S. Speck¹; ¹University of California, Santa Barbara, Mats. Dept., Bldg. E-II, Santa Barbara, CA 93110 USA; ²University of California, Santa Barbara, ECE Dept., Bldg. E-I, Santa Barbara, CA 93110 USA

2:50 PM +

MOCVD Growth and Characterization of AlInGaIn Quaternary Alloys: *Michael E. Aumer*¹; S. F. LeBoeuf¹; F. G. McIntosh¹; Y. C.

Chang¹; J. F. Muth¹; R. M. Kolbas¹; S. M. Bedair¹; ¹North Carolina State University, Dept. of Elect. and Comp. Eng., Box 7911, Raleigh, NC 27695 USA

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Behavior of Quantum Well Excitons Under Internal Fields of GaN/AlGa_N and InGa_N/Ga_N/AlGa_N Quantum Well Structures: *Shigefusa F. Chichibu*¹; Takahiro Deguchi²; Takayuki Sota²; Steven P. DenBaars³; Shuji Nakamura⁴; ¹Science University of Tokyo, Elect. Eng. Dept., Faculty of Sci. and Tech., 2641 Yamazaki, Noda, Chiba 278-8510 Japan; ²Waseda University, Dept. of Elect., Electronics, and Comp. Eng., 3-4-1, Ohkubo, Shinjuku, Tokyo 169-8555 Japan; ³University of California, Santa Barbara, Mats. and ECE Depts., Santa Barbara, CA 93106-5050 USA; ⁴Nichia Chemical Industries, Research and Development Dept., 491 Oka, Kaminaka, Anan, Tokushima 774-8601 Japan

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Piezoelectric Effects in the Radiative Centers of GaIn_N/Ga_N Quantum Wells and Devices: *Christian Wetzel*¹; Tetsuya Takeuchi¹; Hiroshi Amano¹; Isamu Akasaki¹; ¹Meijo University, High Tech Research Center, 1-501 Shiogamaguchi, Tenpaku-ku, Nagoya, Aichi 468-8502 Japan

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Phase Separation in InGa_N/Ga_N MQWs: *L. T. Romano*¹; M. D. McCluskey²; T. Suski³; J. Jun³; ¹Xerox Palo Alto Research Center, 3333 Coyote Rd., Palo Alto 94304 CA; ²Washington State University, Dept. of Shock Phys., Pullman 99164-2814 WA; ³Unipress, UI, Sokolowska 29, 01-142 Warsaw Poland

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Role of Below Bandgap States in the Radiative Emission of InGa_N/Ga_N Quantum Well Structures: *Georgiy O. Vaschenko*¹; Milan S. Minsky²; Dinesh Patel¹; Luiz S. Assis¹; Robert L. Pidcock¹; Carmen S. Menoni¹; Stacia Keller²; Evelyn L. Hu²; Steven P. DenBaars²; ¹Colorado State University, Dept. of Elect. Eng., Fort Collins, CO 80523 USA; ²University of California, Santa Barbara, Dept. of Mats. Eng. and Elect. and Comp. Eng., Santa Barbara, CA 93106 USA

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Optical Band Gap Dependence on Thickness and Composition of InGa_N Grown on Ga_N: *Christopher Arlen Parker*¹; Mason J. Reed²; John C. Roberts¹; Sandra X. Liu²; N. A. El-Masry²; S. M. Bedair¹; ¹NC State University, Elect. and Comp. Eng., 232 Daniels Hall, Box 7911, Raleigh, NC 27695 USA; ²NC State University, Mats. Sci. and Eng., 232 Riddick Labs, Box 7916, Raleigh, NC 27695 USA

Session S. Silicon Carbide Processing for Devices

Session Chairs: Michael A. Capano, Purdue University, School of ECE, W. Lafayette, IN USA; Tom Jackson, Penn State University, University Park, PA USA

1:30 PM

Phosphorus and Nitrogen Implantation into 4H-SiC: *Michael A. Capano*¹; Rajkumar Santhakumar¹; Mrinal K. Das¹; James A. Cooper¹; Michael R. Melloch¹; ¹Purdue University, School of Elect. and Comp. Eng., 1285 Elect. Eng. Bldg., West Lafayette, IN 47907-1285 USA

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Hydrogen Passivation of Aluminum and Boron Acceptors in SiC by Low Energy Ion Implantation: *Norbert Achtziger*¹; Christian Huelsen¹; Wolfgang Witthuhn¹; Margareta K. Linnarsson²; Martin Janson²; Bengt G. Svensson²; ¹University Jena, Institut fuer Festkoerperphysik, Max-Wien-Platz 1, Jena D- 07743 Germany; ²Royal Institute of Tech., Solid State Electronics, Electrum 229, Kista-Stockholm S-16440 Sweden

2:10 PM +

Effect of Implant Activation Annealing Conditions on the Inversion Channel Mobility in 4H- and 6H-SiC MOSFETs: *Mrinal Kanti Das*¹; Michael A. Capano¹; James A. Cooper¹; Michael R. Melloch¹; ¹Purdue University, School of Elect. and Computer Eng., 1285 Elect. Eng. Bldg., West Lafayette, IN 47907-1285 USA

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Electrical Characteristics of Schottky Barriers on 4H-SiC: The Effects of Barrier Height Nonuniformity: *B. J. Skromme*¹; E. Luckowski¹; K. Moore¹; M. Bhatnagar¹; C. E. Weitzel¹; T. Gehoski¹; D. Ganser¹; ¹Motorola, Inc., Mats. Tech. Laboratories, EL720, 2100 E. Elliot Rd., Tempe, AZ 85284 USA

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Characteristics of Nickel Schottky Junctions on Trench Sidewalls of Reactive Ion Etched 4H-SiC Surfaces: *V. Khemka*¹; T. P. Chow¹; R. J. Gutmann¹; ¹Rensselaer Polytechnic Institute, Center for Integrated Electrs. and Electr. Manufacturing, Troy, NY 12180-3590

3:10 PM Break

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High Rate Etching of Silicon Carbide: *F. Khan*¹; L. Zhou¹; A. T. Ping¹; I. Adesida¹; ¹University of Illinois at Urbana-Champaign, Dept. of Elect. and Comp. Eng., 208 N Wright St., Urbana, IL 61801-2355 USA

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Fast, Smooth, and Anisotropic Etching of SiC using SF₆/Ar: *Myeong S. So*¹; Seung-Gu Lim¹; Thomas N. Jackson¹; ¹The Pennsylvania State University, Dept. of Elect. Eng., 121 Elect. Eng. East, University Park, PA 16802 USA

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Analysis of the Temperature Dependence of the SiO₂ / SiC Barrier Height: *Richard Waters*¹; Bart Van Zeghbroeck¹; ¹University of Colorado, Dept. of Elect. and Comp. Eng., Boulder 80309-0525 CO USA

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Atomic-Scale Mechanisms of Oxygen Precipitation and Thin-Film Oxidation of SiC: *Massimiliano Di Ventra*¹; Sokrates T. Pantelides¹; ¹Vanderbilt University, Physics and Astronomy, Stevenson Center, Nashville, TN 37235 USA

4:50 PM Late News

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**Session T. Materials Integration:
Growth and Characterization**

Session Chairs: Theresa Mayer, Penn State University, University Park, PA USA; Matt Seaford, Air Force Research Laboratory, WPAFB, OH USA

1:30 PM

Lattice-Mismatched InGaAs Layers Grown on GaAs and InP Compliant Substrates: *Koen Vanhollebeke*¹; Ingrid Moerman¹; Peter Van Daele¹; Piet Demeester¹; ¹University of Gent-IMEC, Dept. of Information Tech. (INTEC), Sint-Pietersnieuwstraat 41, Gent, - 9000 Belgium

1:50 PM

A Comparison of Experimental and Calculated HRXD Spectra of Mismatched InGaAs Films Grown on Borosilicate Glass-Bonded GaAs Compliant Substrate Structures: *P. D. Moran*¹; D. M. Hansen¹; J. G. Cederberg¹; K. A. Dunn¹; L. J. Mawst¹; S. E. Babcock¹; R. J. Matyi¹; T. F. Kuech¹; ¹University of Wisconsin, 1415 Johnson Dr., Madison, WI 53706 USA

2:10 PM +

Strain Relaxation in In_xGa_{1-x}As Lattice Engineered Substrates: *Prashant M Chavarkar*¹; Lijie Zhao²; Stacia Keller¹; Andrew Fisher³; James S. Speck²; Umesh K. Mishra¹; ¹University of California, Dept. of Elec. and Comp. Eng., Santa Barbara, CA 93106 USA; ²University of California, Mats. Dept., Santa Barbara, CA 93106 USA; ³University of California, QUEST, Santa Barbara, CA 93106 USA

2:30 PM +

On the Strain Relaxation and Misfit Dislocation Introduction Mechanisms in Highly Lattice Mismatched InAs/GaP Epitaxy: *Vidyut Gopal*¹; Alexander L. Vasiliev¹; Enhsing Chen²; Eric P. Kvam¹;

Jerry M. Woodall²; ¹Purdue University, School of Mats. Eng., 1289, MSEE Bldg., W. Lafayette, IN 47907 USA; ²Yale University, Dept. of Elect. Eng., 15, Prospect St., P.O. Box 208284, New Haven, CT 06520-8284 USA

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Comparison of InGaSb/InAs Superlattice Structures Grown by MBE on GaSb, GaAs, and Compliant GaAs Substrates: *D. H. Tomich*¹; K. G. Eyink¹; G. L. Brown¹; L. Grazulis¹; K. Mahalingam¹; M. L. Seaford¹; C. H. Kuo²; W-Y. Hwang²; C. H. Lin²; ¹Air Force Research Laboratory, Mats. and Manufacturing Directorate, 3005 P St. Suite 6, WPAFB, OH 45433-7707; ²Applied Optoelectronics Inc., Sugar Land, TX 77478

3:50 PM

Low Dislocation Relaxed SiGe Grown on a Novel Compliant Substrate: *Yuhao Luo*¹; Jian-Lin Liu¹; Gaolong Jin¹; Kang L. Wang¹; Chih Chen²; King-Ning Tu²; Caroline D. Moore²; Mark S. Goorsky²; ¹University of California at Los Angeles, Dept. of Elect. Eng., Eng. IV 17-142, 405 Hilgard Ave., Los Angeles, CA 90095-1594 USA; ²UCLA, Dept. of Mats. Sci. and Eng., 6532 Boelter Hall, 405 Hilgard Ave., Los Angeles, CA 90095-1595 USA

4:10 PM

Optically-Pumped Mid-Infrared Lasers on Traditional and Compliant Substrates: *Stefan J. Murry*¹; Chau-Hong Kuo¹; Chih-Hsiang Lin¹; Han Q. Le¹; Shin-Shem Pei¹; ¹University of Houston, Space Vacuum Epitaxy Center, SR1 Rm. 724, 4800 Calhoun, Houston, TX 77204-5507 USA

4:30 PM

Optically Pumped Stimulated Emission in Freestanding GaN Prepared by Hydride Vapor Phase Epitaxy: *S. T. Kim*¹; D. C. Moon²; C. K. Kim³; Y. H. Choi³; T. K. Yoo³; ¹Taejon National University of Tech., Dept. of Mats. Eng., 305-3 Samsung-dong, Dong-gu, Taejon 300-717 Korea; ²Kwangwoon University, Dept. of Electr. Mats. Eng., 447-1 Wolgye-dong, Nowon-gu, Seoul 139-701 Korea; ³LG Corporate Institute of Tech., Optoelectronic Group, 16 Woomyeon-dong, Seocho-gu, Seoul 137-724 Korea

4:50 PM Late News

Session U. Thermophotovoltaic Materials & Devices

Session Chairs: L. Ralph Dawson, UNM-CHTM, Albuquerque, NM USA; Parvez Uppal, Lockheed Martin, Nashua, NH USA

1:30 PM

Photon Recycling in 0.53 eV InGaAsSb: *Greg Walter Charache*¹; ¹Lockheed Martin, Knolls Atomic Power Laboratory, River Rd., Schenectady, NY 12065-1072 USA

1:50 PM

Spectral Ellipsometry of GaSb and GaInAsSb/GaSb: Experiment and Modelling: *Martin Munoz*¹; K. Wei¹; Fred H. Pollak¹; Greg Charache²; C. A. Wang³; ¹Brooklyn College of CUNY, Phys. Dept., 3438N, 2900 Bedford Ave., Brooklyn, NY 11210 USA; ²Lockheed Martin, Schenectady, NY 12301 USA; ³MIT Lincoln Laboratory, Lexington, MA 02420 USA

2:10 PM

Phase Instabilities and Microstructure in InGaAsSb/GaSb Heterostructures: Y-C Chen¹; V. Bucklen¹; *Krishna Rajan*¹; C. Wang²; G. Nichols³; P. Sander³; G. Charache³; ¹Rensselaer Polytechnic Institute, Mats. Sci. and Eng. Dept., Bldg. MRC-110, Troy, NY 12180-3590 USA; ²Lincoln Laboratories, Lexington, MA 02420-1072 USA; ³Lockheed-Martin Corporation, Schenectady, NY 12301-1072 USA

2:30 PM

OMVPE Growth of InGaAsSb Thermophotovoltaic Cells: N. A. Morris¹; Z. A. Shellenbarger²; D. Z. Garbuzov¹; R. U. Martinelli¹; V. B. Khalfin¹; H. Lee¹; G. C. Taylor¹; G. S. Tompa²; J. C. Connolly¹; ¹Sarnoff Corporation, 201 Washington Rd., Princeton, NJ 08543; ²Structured Mats. Industries, Inc., 120 Centennial Ave., Piscataway, NJ 08854

2:50 PM

A Study of the Relative Tilt of GaInSb Epitaxial Layers on GaSb Substrates Grown by Metalorganic Vapor Phase Epitaxy: *Ishwara B. Bhat*¹; Hassan Ehsani¹; Ronald Gutmann¹; Greg Charache²; Mathew Freeman²; ¹Rensselaer Polytechnic Inst., ECSE Dept., JEC 6003, 110 8th St., Troy, NY 12180 USA; ²Lockheed Martin Corporation, Schenectady, NY 12301

3:10 PM Break

**Session V. Thermoelectric and Other
Narrow Gap Materials**

Session Chairs: Tim Sands, University of California-Berkeley, MS & ME Dept., Berkeley, CA USA; Kang Wang, University of California, EE Dept., Los Angeles, CA USA

3:30 PM

MOCVD Growth of High Mobility InSb on Si Substrates for Hall Effect Applications.: *Michael W. Peleczynski*¹; Jean J. Heremans¹; ¹Emcore Corporation, ERA, 394 Elizabeth Ave., Somerset, NJ 08873 USA

3:50 PM

The Effect of Annealing Temperature on the Structural and Electrical Properties of Au/n-GaSb Contacts: *H. Ehsani*¹; C. Hitchcock¹; R. J. Gutmann¹; I. Bhat¹; G. Charache²; M. Freeman²; ¹Rensselaer Polytechnic Institute, Elect., Comp., and System Eng., Troy, NY 12180 USA; ²Lockheed Martin Corporation, Schenectady, NY 12301-1072 USA

4:10 PM

300K Thermoelectric Figure of Merit in the Range of 3 Utilizing Phonon-Blocking Electron-Transmitting Structures: *Rama Venkatasubramanian*¹; Edward Siivola¹; Thomas Colpitts¹; ¹Research Triangle Institute, Center for Semiconductor Research, 3040 Cornwallis Rd., Research Triangle Park, NC 27709 USA

4:30 PM

Thermoelectric Quantum Dot Superlattices: *T. C. Harman*¹; P. J. Taylor¹; D. L. Spears¹; M. P. Walsh¹; ¹MIT Lincoln Laboratory, P.O. Box 73, Lexington, MA 02420-9180 USA

4:50 PM

Temperature Dependence of Thermionic Emission Cooling in Single Barrier and Superlattice Heterostructures: *Ali Shakouri*¹; Chris LaBounty²; Patrick Abraham²; Yi-Jen Chiu²; John E. Bowers²; ¹University of California, Jack Baskin School of Eng., 1156 High St., Santa Cruz, CA 95064 USA; ²University of California, ECE Dept., Santa Barbara, CA 93106 USA

Session W. Epitaxy of III-V

Session Chair: Jenn-ming Kuo, Bell Labs, Murray Hill, NJ USA

8:20 AM

Structural and Optical Properties of Strained InGaAs/GaAs Quantum Wells Grown by MOVPE on (111)A GaAs Substrates: *Soohaeng Cho*¹; A. Majerfeld¹; A. Sanz-Hervás¹; B. W. Kim⁴; C. Villar²; Jongseok Kim¹; ¹University of Colorado, Dept. of Elect. and Comp. Eng., CB425, Boulder, CO 80309 USA; ²E.T.S.I. Telecomunicación, UPM, Departamento de Tecnología Electrónica, Ciudad Universitaria, 28040 Madrid, Spain; ⁴Electronics and Telecommunications Research Institute, P.O. Box 106, Yusong, Taejon, 305-600 Korea

8:40 AM +

An Investigation on the Mechanisms Responsible for Ar⁺-Laser Induced Growth Enhancement Of GaAs by Chemical Beam Epitaxy: *Bin Q. Shi*¹; Charles W. Tu¹; ¹University of California, San Diego, Dept. of Elect. and Comp. Eng., 9500 Gilman Dr., La Jolla, CA 92093-0407 USA

9:00 AM

Enhancement of Electron Mobilities in Pseudomorphic In_{0.7}Ga_{0.3}As/In_{0.52}Al_{0.48}As Modulation-doped Quantum Wells with (411)A Super-flat Interfaces Grown by Molecular Beam Epitaxy: *Takahiro Kitada*¹; Masato Ueno¹; Toyohiro Aoki¹; Satoshi Shimomura¹; Satoshi Hiyamizu¹; ¹Osaka University, Graduate School of Eng. Sci., 1-3 Machikaneyama, Toyonaka, Osaka 560-8531 Japan

9:20 AM

High Quality GaAs_{0.68}P_{0.32}/In_{0.13}Ga_{0.87}P/Si QW Structure with a Very Few Threading Dislocations: *Yasuhiro Fujimoto*¹; Hiroo Yonezu¹; Naoki Ohshima¹; Kenji Momose¹; ¹Toyohashi University of Technology, Dept. of Elect. and Electr. Eng., 1-1 Hibarigaoka, Tempaku-cho, Toyohashi, Aichi 441-8580 Japan

9:40 AM +

Dependence of Cracker Temperature to Silicon During Concentration in InGaAlP Layers Grown by Solid Source Molecular Beam Epitaxy: *Yi-Cheng Chengis*¹; Kuo-chou Tai¹; S. T. Chou²; K. F. Huang³; *W. J. Lin*⁴; *W. H. Lan*⁴; A. C. H. Lin⁴; *T. C. Wang*⁴; ¹National Chiao-Tung University, Institute of Opto-Elect. Eng., 1001, Ta-Hsieh Rd., HsinChu, Taiwan ROC; ²Chung-Cheng Institute of Technology, Dept. of Elect. Eng., Tahsi, Taoyuan, Taiwan ROC; ³National Chiao-Tung University, ElectroPhysics Dept., 1001, Ta-Hsieh, HsinChu, Taiwan ROC; ⁴Chung Shang Institute of Science and Technology, Material R & D Center, Lun-Tang P.O. Box 90008-8-6, Taoyuan, Taiwan ROC

10:00 AM Break

Session X. Composite Materials and Applications

Session Chairs: Daniel Docter, HRL Laboratories, Malibu, CA USA; Jerry Woodall, Yale University, New Haven, CT USA

10:20 AM +

Transit Time and Light Absorption Effects in ITG-GaAs and Applications to MSM-Photodetectors: *Vijay Krishnamurthy*¹; Marian C. Hargis²; Michael R. Melloch²; ¹Purdue University, School of Elect. and Comp. Eng., Mailbox #258, West Lafayette, IN 47907-1285 USA; ²Purdue University, School of Elect. and Comp. Eng., West Lafayette, IN 47907-1285 USA

10:40 AM +

Ultrafast Carrier Dynamics in Be-Doped Low Temperature Grown GaAs Studied by Double-Pulse Excitation: *Ri-an Zhao*¹; Petra Specht¹; Eicke R. Weber¹; Nen-Wen Pu²; Jeff Bokor²; ¹University of California-Berkeley, Dept. of Mats. Sci. and Eng., 211-226 Cory Hall #1772, Dept. of EECS, Berkeley, CA 94720 USA; ²University of California, Dept. of Elect. Eng. and Comp. Sci., Berkeley, CA 94720 USA

11:00 AM +

Experimentally Verified Conduction Model for a Low-Resistance Non-Alloyed Ohmic Contact Utilizing Low-Temperature-Grown GaAs: *N.-P. Chen*¹; H. J. Ueng²; D. B. Janes²; K. J. Webb²; M. R. Melloch²; ¹Purdue University, Dept. of Phys., 1396 Phys. Bldg., West Lafayette, IN 47907 USA; ²Purdue University, School of Elect. and Comp. Eng., 1285 Elect. Eng. Bldg., West Lafayette, IN 47907 USA

11:20 AM +

Thermal Conductivity of Low-Temperature-Grown GaAs: *Andrew W. Jackson*¹; James P. Ibbetson²; Arthur C. Gossard¹; Umesh K. Mishra²; ¹University of California, Mats. Dept., Santa Barbara, CA 93106 USA; ²University of California, ECE Dept., Santa Barbara, CA 93106 USA

11:40 AM

Surface Atomic Process of Incorporation of Excess Arsenic in Molecular Beam Epitaxy of GaAs: A. Suda¹; N. Otsuka¹; ¹Japan Advanced Institute of Science and Technology, School of Mats. Sci., Asahidai -1, Tatsunokuchi, Nomigun, Ishikawa 923-1292 Japan

Session Y. Properties of Quantum Wires and Wells

Session Chairs: Jim Merz, University of Notre Dame, Notre Dame, IN USA; Clivia Sotomayor-Torres, University of Wuppertal, Institute of Mats. Sci. & Dept. of Elect. Eng., Wuppertal, Germany

8:20 AM

Structural and Alloy Composition Uniformity of InGaAs Ridge Quantum Wires Grown by Selective MBE on Patterned InP Substrates: *Chao Jiang*¹; Hajime Fujikura¹; Tsutomu Muranaka¹; Hideki Hasegawa¹; ¹Hokkaido University, Research Center for Interface Quantum Electronics and Graduate School of Electronics and Information Eng., North 13, West 8, Kita Ku, Sapporo, Hokkaido 060-8628 Japan

8:40 AM

Spin Splitting of Exciton Band in Asymmetric Double Quantum Wells: Guangyou Yu¹; Xiwu Fan¹; Jiying Zhang¹; Dezhen Shen¹; ¹Changchun Institute of Physics, Chinese Academy of Sciences, Laboratory of Excited State Processes, 1 Yan An Rd., Changchun, Jilin 130021 ROC

9:00 AM

Mobility Edge and Exciton Relaxation in CdSe/ZnSe Quantum Wells: *Jinxi Shen*¹; R. Pittini¹; K. Yui¹; I. Souma¹; Y. Oka¹; E. Kurtz²; T. Yao³; ¹Tohoku University, Research Institute for Scientific Measurements, Katahira 2-1-1, Sendai, Miyagi 980-8577 Japan; ²University of Karlsruhe, Institute for Applied Phys., Karlsruhe D-76128 Germany; ³Tohoku University, Institute for Mats. Research, Katahira 2-1-1, Sendai, Miyagi 980-8577 Japan

9:20 AM

Recombination Lifetime Measurements of InGaN/GaN Multiple Quantum Wells: *Eun-joo Shin*¹; N. W. Song¹; J. I. Lee¹; D. Kim¹; M. Y. Ryu²; P. W. Yu²; D. Lee³; Y. -H. Choi⁴; C. -H. Hong⁵; ¹Korea Research Institute of Standards and Sci., Spectroscopy Group, Yusongku, P.O. Box 102, Taejon 305-600 Korea; ²K-JIST, Dept. of Information & Communications, Kwangju 506-712 Korea; ³Chungnam National University, Dept. of Phys., Taejon 305-764 Korea; ⁴L. G. CIT, Optoelectronics Group, Seoul 137-140 Korea; ⁵Jeonbuk National University, SPRC, Jeonju 560-756 Korea

9:40 AM

Study of Temperature-Dependent Photocurrent and Dark Current Measurements for a Maximization of Carrier Collection and a Voltage Enhancement of MQW P-I-N Diodes: *Cedric Monier*¹; *Frederick Newman*¹; Inna Serdiukova¹; Lissandro Aguilar¹; Mauro F. Vilela¹; Alexandre Freundlich¹; ¹University of Houston, Space Vacuum Epitaxy Center, 4800 Calhoun St., Sci. & Research I, Houston, TX 77204-5507 USA

10:00 AM Break

10:20 AM

Improved Heterointerface Quality of AlGaAs/GaAs Quantum Wires Characterized by AFM and Microscopic Optical Measurements: *Xue-Lun Wang*¹; Mutsuo Ogura¹; Valia Voliotis²; Roger Grousson²; ¹Japan Science and Technology Corporation, Electrotechnical Laboratory and CREST, , 1-1-4 Umezono, Tsukuba, Ibaraki 305 Japan; ²Groupe de Physique des Solides, CNRS, Universities Paris 6 and Paris 7, 2 place Jussieu, F-75251, Paris Cedex 05 France

10:40 AM

Optical Properties in InGaN/GaN Structures Grown by Metal-Organic Chemical Vapor Deposition: *Mee Yi Ryu*¹; Eun-joo Shin²; J. H. Song¹; S. W. Park¹; P. W. Yu¹; N. W. Song²; J. I. Lee²; D. Kim²; E. S. Oh³; Y. J. Park³; H. S. Park³; T. I. Kim³; ¹Kwangju Institute of Science and Technology, Dept. of Information and Communications, 1 Oryong-dong, Puk-gu, Kwangju 500-712 ROK; ²Korea Research Institute of Standards and Science, Spectroscopy Group, P.O. Box 102, Taejon 305-600 ROK; ³Samsung Advanced Institute of Technology, Photonics Laboratory, P.O. Box 111, Suwon 440-600 ROK

11:00 AM

Modulation Spectroscopy Study of a Strained Layer GaAs/GaAsP Multiple Quantum Well Structure: *L. Malikova*¹; Fred H. Pollak¹; Oleg Gorea²; Alexander Korotcov²; ¹Brooklyn College of CUNY, Phys. Dept., 3438N, 2900 Bedford Ave., Brooklyn, NY 11210-2889 USA; ²State University of Moldova, Dept. of Phys., Chisinau, MD 2009 Moldova

11:20 AM

The Annealing Effects on Optical and Structural Properties of (ZnSe)₂(CdSe)_n Short-Period-Superlattices Multiple Quantum Wells: *Ru Chin TU*¹; Yan Kuin SU¹; Shu Tsun Chou²; ¹National Cheng-Kung University, Dept. of Elect. Eng., 1, University Rd., Tainan City 703 Taiwan; ²Chung Cheng Institute of Technology, Dept. of Elect. Eng., Taoyuan 335 Taiwan

11:40 AM +

Transient Luminescence and Exciton Dynamics in (CdMn)Te/(CdMg)Te Quantum Wells: *Mukul C. Debnath*¹; J. X. Shen¹; I. Souma¹; E. Shirado¹; T. Saito¹; T. Sato¹; R. Pittini¹; Y. Oka¹; ¹Tohoku University, Research Institute for Scientific Measurements, Katahira 2-1-1, Sendai, Miyagi 980-8577 Japan

Friday AM, July 2, 1999

Session Z. Wide Bandgap Nitrides (MBE, Theory, and AlN)

Session Chairs: Chris van der Walle, Xerox Palo Alto, CA USA; Russell Dupuis, University of Texas, Austin, TX USA

8:20 AM +

Dielectric and Lattice-Dynamical Properties of III-Nitrides: *Ulrike Grossner*¹; Jurgen Furthmuller¹; Friedhelm Bechstedt¹; ¹Friedrich-Schiller-Universitaet, IFTO, Max-Wien-Platz 1, Jena 07743 Germany

8:40 AM

Pressure Coefficient of Nitrides and Their III-V Alloys: *Su-Huai Wei*¹; T. Mattila¹; A. Zunger¹; ¹National Renewable Energy Laboratory, 1617 Cole Blvd., Golden, CO 80401 USA

9:00 AM

Measurement of Al Mole Fraction of Bulk AlGaN and AlGaN/GaN Heterostructures by Photoconductance and Reflectance Methods: *L. S. Yu*¹; D. Qiao¹; S. S. Lau¹; J. M. Redwing²; ¹University of California, San Diego, Dept. of Elect. and Comp. Eng., 9500 Gilman Dr., La Jolla, CA 92093-0407 USA; ²ATMI, Epitronics, 21002 North 19 Ave., Suite 5, Phoenix, AZ 85027 USA

9:20 AM +

Growth of Bulk AlN by Physical Vapor Transport: *Tim Housain*¹; P. Zhou¹; H. N. Jayatirtha¹; M. G. Spencer¹; V. Dmitriev²; Yu Melnik²; A. Nikolaev³; ¹Howard University School of Engineering, Rm. 1124 Material Sci. Center, 2300 6th St. NW., Washington, DC 20059 USA; ²TDI Inc., 8660 Dakota Drive, Gaithersburg, MD 20877 USA; ³A. F. Ioffe Institute, 26 Polytechnicheskaya St., St. Petersburg Russia

9:40 AM

Microstructural Analysis of the Recrystallization in AlN Nucleation Layers: *Yves-Matthieu Le Vaillant*¹; René Bisaro²; Jean Olivier³; Pierre Galtier⁴; Jean-Yves Duboz⁵; Bernard Gil⁶; Sandra Ruffenach-Clur⁷; Olivier Briot⁸; Roger-Louis Aulombard⁹; ¹Thomson-CSF/University Montpellier, Laboratoire Central de Recherches/GES, Université de Montpellier II, pl. E. Bataillon, GES, cc074, Montpellier 34095 France; ²Thomson-CSF, Laboratoire Central de Recherches, Domaine de Corbeville, Orsay 91 404 France; ³Thomson-CSF, Laboratoire Central de Recherches, Domaine de Corbeville, Orsay 91404 France; ⁴Thomson-CSF, Laboratoire Central de Recherches, Domaine de Corbeville, Orsay 91404 France; ⁵Thomson-CSF, Laboratoire Central de Recherches, Domaine de Corbeville, Orsay 91404 France; ⁶Université de Montpellier, Groupe d'Etude des Semiconducteurs, pl. E. Bataillon, Montpellier 34095 France; ⁷Université de Montpellier, Groupe d'Etude des Semiconducteurs, pl. E. Bataillon, Montpellier 34095 France; ⁸Université de Montpellier, Groupe d'Etude des Semiconducteurs, pl. E. Bataillon, Montpellier 34095 France; ⁹Université de Montpellier, Groupe d'Etude des Semiconducteurs, pl. E. Bataillon, Montpellier 34095 France

10:00 AM Break**10:20 AM**

Lateral Epitaxial Overgrowth of GaN Films by Molecular Beam Epitaxy: *M. R. Hoit*¹; A. M. Dabiran²; B. E. Ishaug¹; A. Parkhomovsky¹; R. Held¹; P. I. Cohen¹; ¹University of Minnesota, Elect. and Comp. Eng., 200 Union St. SE, Minneapolis, MN 55455 USA; ²Silver Sky Technologies, Inc., 644 Pond View Terrace, St. Paul, MN 55120 USA

10:40 AM

Strain Relaxation and Homogeneity of AlGaN Grown by Molecular Beam Epitaxy: *Sven Einfeldt*¹; Kai Vogeler¹; Verena Kirchner¹; Tim Boettcher¹; Heidrun Heinke¹; Detlef Hommel¹; Dirk Rudloff²; Juergen Christen²; ¹University of Bremen, Institute of Solid State Phys., P.O. Box 330440, Bremen 28334 Germany; ²University of Magdeburg, Institute of Experimental Phys., P.O. Box 4120, Magdeburg 39016 Germany

11:00 AM +

Surfactant Effect and Polarity Inversion Due to Mg on the GaN(0001) Surface: *V. Ramachandran*¹; R. M. Feenstra¹; D. W. Greve²; J. E. Northrup³; ¹Carnegie Mellon University, Dept. of Phys., Pittsburgh, PA 15213 USA; ²Carnegie Mellon University, Dept. of Elect. and Comp. Eng., Pittsburgh, PA 15213 USA; ³Xerox, Palo Alto Research Center, 3333 Coyote Hill Rd., Palo Alto, CA 94304 USA

11:20 AM

Influence of Structural Defects on Transport Properties of GaN Grown by Reactive MBE and Magnetron Sputter Epitaxy (MSE): *Haipeng Tang*¹; James B. Webb¹; Jennifer Bardwell¹; Brian Leathem¹; Sylvain Charbonneau¹; Sylvain Raymond¹; ¹National Research Council, Institute for Microstructural Sciences, Bldg. M-50, Montreal Rd., Ottawa, Ontario K1A 0R6 Canada

11:40 AM +

Optimization of High Quality GaN by MBE: *B. Heying*¹; I. Smorchkova²; C. Elsass¹; E. Haus¹; P. Fini¹; T. Mates¹; S. P. DenBaars¹; U. Mishra²; J. S. Speck¹; ¹UC Santa Barbara, Mats. Dept., Santa Barbara, CA 93106 USA; ²UC Santa Barbara, ECE Dept., Santa Barbara, CA 93109 USA

Friday AM, July 2, 1999

Session AA. Metal Contacts to Wide Band Gap Semiconductors

Session Chairs: Suzanne Mohney, Penn State University, University Park, PA USA; Lisa Porter, Carnegie Mellon University, Dept. of Mats. Sci. & Eng., Pittsburgh, PA USA; Louis Guido, Carnegie Mellon University, Dept. of Mats. Sci. & Eng., Pittsburgh, PA USA

8:20 AM

Large Schottky Barriers and Memory Operation for Ni/p-GaN Contacts: *Kenji Shiojima*¹; Tomoya Sugahara²; Shiro Sakai²; ¹NTT, Photonics Laboratories, 3-1 Morinosato Wakamiya, Atsugi-shi, Kanagawa 243-0198 Japan; ²Tokushima University, Dept. of Elect. and Electr. Eng., 2-1 Minami-josanjima, Tokushima, 770-8506 Japan

8:40 AM +

High Temperature Behavior of Barrier Height and Ideality Factor of Ni/Au Contacts to P-Type GaN: *Ricky Wenkuei Chuang*¹; Albert Q. Zou¹; Jeffrey D. Nay¹; YongSheng Zhao¹; Henry P. Lee¹; Z. J. Dong²; F. F. Xiong²; Robert Shih²; M. Bremser³; ¹University of California, Irvine, Dept. of Elect. and Comp. Eng., 3333 Eng. Gateway Westwing, Irvine, CA 92697 USA; ²Alpha Photonics Inc., 2019 Saturn St., Monterey Park, CA 91754 USA; ³AIXTRON Inc., 1670 Barclay Blvd., Buffalo Grove, IL 60089 USA

9:00 AM

Current Transport Mechanism of Low-Resistance TaTi Ohmic Contact Materials for P-GaN: *Yasuo Koide*¹; M. Suzuki¹; T. Arai¹; Y. Matsunaga¹; T. Kawakami¹; Masanori Murakami¹; T. Uemura²; N. Shibata²; Y. Taga³; ¹Kyoto University, Dept. of Mats. Sci. and Eng., Sakyo-ku,

Kyoto 606-8501 Japan; ²Toyoda Gosei Co. Ltd, Optoelectronics, Technical Dept. No. 2, Heiwa-cho, Nakashima-gun, Aichi 490-1312 Japan; ³Toyota Central Research & Development Labs. Inc., Nagakute, Aichi 048-1192 Japan

9:20 AM +

Indium Tin Oxide as a Transparent Contact to P-GaN: Tal Margalith¹; *Oded Buchinsky*²; Dan A. Cohen²; Amber C. Abare²; Monica Hansen¹; Steven P. DenBaars¹; Larry A. Coldren²; ¹University of California at Santa Barbara, Dept. of Mats., Santa Barbara, CA 93106 USA; ²University of California at Santa Barbara, Dept. of ECE, Santa Barbara, CA 93106 USA

9:40 AM +

Surface Treatment of P-GaN by KOH Solution Studied by Synchrotron Radiation Core-Level Spectroscopy: *Jingxi Sun*¹; K. A. Rickert²; J. M. Redwing³; A. B. Ellis²; F. J. Himpsel⁴; T. F. Kuech¹; ¹University of Wisconsin-Madison, Dept. of Chem. Eng., 1415 Eng. Drive, Madison, WI 53706 USA; ²University of Wisconsin-Madison, Chemistry Dept.; ³Epitronics, Phoenix, Arizona; ⁴University of Wisconsin-Madison, Phys. Dept.

10:00 AM Break

10:20 AM +

Characterization of Rhenium Schottky Contacts on N-Type Al_xGa_{1-x}N at High Temperatures: *L. Zhou*¹; A. T. Ping¹; J. Redwing²; I. Adesida¹; ¹University of Illinois, Dept. of Elect. and Comp. Eng., Microelectronics Lab, MC-249, Urbana, IL 61801-2355 USA; ²ATMI/Epitronics, Phoenix, AZ 85027 USA

10:40 AM

Improved Surface Morphology and Thermal Stability of Al/Ti-n-GaN: *Joon Seop Kwak*¹; Suzanne E. Mohney¹; R. Scott Kern²; ¹The Pennsylvania State University, Dept. of Mats. Sci. and Eng., University Park, PA 16802 USA; ²Hewlett Packard Company, 370 W. Trimble Rd., San Jose, CA 95131-1008 USA

11:00 AM +

A New Approach to Thermodynamically Stable Contacts for Binary Wide Bandgap Semiconductors: *Ilan Shalish*¹; Yoram Shapira¹; Moshe Eizenberg²; ¹Tel-Aviv University, Dept. of Physical Electronics, Tel-Aviv 69978 Israel; ²Thechnion - Israel Institute of Tech., Dept. of Mats. Eng., Haifa 32000 Israel

11:20 AM

Metallization Schemes for High Temperature Electrical Contacts to Silicon Carbide: Taehoon Jang¹; Gerald W. M. Rutsch²; Bruce Odekirk³; *Lisa M. Porter*¹; ¹Carnegie Mellon University, Mats. Sci. & Eng., 5000 Forbes Ave., Pittsburgh, PA 15213-3890 USA; ²University of Pittsburgh, Dept. of Phys., Pittsburgh, PA 15260 USA; ³3C Semiconductor Corporation, 5429 SW Viewpoint Terr., Portland, OR 97201 USA

11:40 AM

Effect of Si_{1-x}C_x Interface Layer on the Properties of Metal Contacts to P-Type SiC: *Johnson Olufemi Olowolafe*¹; Jun Liu¹; Sarbajit Datta¹; ¹University of Delaware, Elect. and Comp. Eng., Newark, Delaware 19716 USA

**Session BB. Etching and Passivation
of Compound Semiconductors**

Session Chairs: Marian Hargis, Purdue University, West Lafayette, IN USA; Carol Ashby, Sandia National Laboratories, Albuquerque, NM USA

8:20 AM +

In Situ Etch and Regrowth of a InAs/AlGaSb Heterostructure: *Giovanni Bellomi*¹; William J. Mitchell¹; Eric Hall¹; Evelyn L. Hu¹; ¹University of California Santa Barbara, QUEST, Santa Barbara, CA 93106-5050 USA

8:40 AM +

Inductively Coupled Plasma Selective Reactive Ion Etching of GaAs/InGaP For Device Fabrication: *W. Lanford*¹; C. Lee¹; G. Cueva¹; L. Zhou¹; I. Adesida¹; Noren Pan²; ¹University of Illinois at Urbana-Champaign, Dept. of Elect. and Comp. Eng., 208 N. Wright St., Urbana, IL 61801-2355; ²Kopin Corporation, Inc., Taunton, MA 02780

9:00 AM

GaAs/AlGaAs Selective Dry Etching by Sawtooth-Wave Modulated Inductively Coupled SiCl₄/SF₆ Plasma: *Yusuke Matsukura*¹; Jun Wada²; Mizuhisa Nihei¹; Hitoshi Tanaka¹; ¹Fujitsu Laboratories Ltd., Compound Semiconductor LSIs Lab., 10-1, Morinosato-Wakamiya, Atsugi, Kanagawa 243-0197 Japan; ²Fujitsu Quantum Devices Ltd., 1000, Kamisukiahara, Showa-cho, Nakakomagun, Yamanashi 409-3883 Japan

9:20 AM

Air-Stable Surface Passivation of III-V Semiconductors and Application to Devices: *Carol I. H. Ashby*¹; Kevin R. Zavadil¹; Albert G. Baca¹; Ping-Chih Chang¹; B. E. Hammons²; Michael J. Hafich¹; ¹Sandia National Laboratories, Dept. 1711, MS 0603, P.O. Box 5800, Albuquerque, NM 87185-0603 USA; ²Emcore West, 10420 Research Rd. SE, Albuquerque, NM 87123 USA

9:40 AM

Effects of Chemical Treatments and Sulfide Passivation on Surface Recombination In GaN: *G. L. Martinez*¹; M. R. Curiel¹; *B. J. Skromme*¹; R. J. Molnar²; ¹Arizona State University, Dept. of Elect. Eng. and Center for Solid State Electronics Research, P.O. Box 876206, Tempe, AZ 85287-6206 USA; ²Lincoln Laboratory, Massachusetts Institute of Tech., Room E-124D, 244 Wood St., Lexington, MA 02173-9108 USA

10:00 AM Break

10:20 AM

Investigation of the Chemisorption and Reaction of Chlorine with the GaN (0001) Surface: *Jingxi Sun*¹; K. A. Rickert²; L. Zhang¹; A. B. Ellis²; F. J. Himpsel³; T. F. Kuech¹; ¹University of Wisconsin-

Madison, Chem. Eng. Dept., 1415 Engineering Dr., Madison, WI 53706 USA; ²University of Wisconsin-Madison, Chem. Dept.; ³University of Wisconsin-Madison, Phys. Dept.

10:40 AM

Photoluminescence Measurements of Dry Etch Damage in GaN: *Elaine D. Haberer*¹; Ching-Hui Chen²; Monica Hansen¹; Evelyn L. Hu²; ¹University of California, Santa Barbara, Mats. Dept., Santa Barbara, CA 93106 USA; ²University of California, Santa Barbara, Elect. and Comp. Eng. Dept., Santa Barbara, CA 93106 USA

11:00 AM

A Simple Wet Etch for GaN: *Jennifer A. Bardwell*¹; Ian G. Foulds¹; James B. Webb¹; Haipeng Tang¹; ¹National Research Council of Canada, IMS, Bldg. M-50, Ottawa, ON K1A 0R6 Canada

11:20 AM

Photoelectrochemical Etching of GaN for Materials Characterization and Device Fabrication: *I. Adesida*¹; C. Youtsey¹; D. Selvanathan¹; T. Pierson¹; A. Daga¹; M. Hossain¹; L. Romano²; ¹University of Illinois at Urbana-Champaign, Dept. of Elect. and Comp. Eng. and Microelect. Lab., 208 N. Wright St., Urbana, IL 61801-2355; ²Xerox PARC, Palo Alto, CA 94304

11:40 AM +

Development of Photoelectrochemical Etching for Gallium Nitride Device Fabrication: *A. R. Stonas*¹; P. Kozodoy¹; C. Chen¹; H. Marchand¹; E. L. Hu¹; ¹University of California at Santa Barbara, QUEST/Elect. and Comp. Eng., University of California, ECE Dept., Box 14, Santa Barbara, CA 93106 USA

Friday AM, July 2, 1999

Session CC. Defects and Defect Engineering for Devices

Session Chairs: Steven A. Ringel, The Ohio State University, Dept. of Elect. Eng., Columbus, OH USA; Steve Stockman, Hewlett-Packard Optoelectronics Division, San Jose, CA USA

8:20 AM +

Wafer Edge Misfit Dislocation Nucleation in p/p+ Vapor Phase Silicon: *Petra Feichtinger*¹; Hiroaki Fukuto¹; Mark S. Goorsky¹; Dwain Oster²; Jim Moreland²; Mohan Rao²; ¹University of California, Los Angeles, Dept. of Mats. Sci. and Eng., School of Eng. and Applied Sci., 2521 Boelter Hall, Los Angeles, CA 90095-1595 USA; ²Wacker Siltronic Corp., 7200 NW Front Ave., Portland, OR 97283

8:40 AM

Reduction of Defect Induced Leakage Currents by the Use of Nitrided Field Oxides in Selective Epitaxial Growth (SEG) Isolation for Silicon ULSI: *Rashid Bashir*¹; Tai-chi Su¹; Gerold W. Neudeck¹; John P. Denton¹; ¹Purdue University, Elect. and Comp. Eng., 1285 EE Bldg., W. Lafayette, IN 47906 USA

9:00 AM +

Selective SiGe Nanostructures Grown by UHVCVD: *Thomas Andrew Langdo*¹; Matthew T. Currie¹; Gianni Taraschi¹; Eugene A. Fitzgerald¹; ¹Massachusetts Institute of Tech., Dept. of Mats. Sci. and Eng., 77 Massachusetts Ave., Cambridge, MA 02139 USA

9:20 AM +

Minority Carrier Properties and Defects in MBE-Grown AlGaAs/GaAs Heterostructures on Ge: *John A. Carlin*¹; John J. Boeckl¹; Steven A. Ringel¹; Brian M. Keyes²; ¹The Ohio State University, Elect. Eng., 2015 Neil Ave., Columbus, OH 43210 USA; ²National Renewable Energy Laboratory, Golden, CO 80401 USA

9:40 AM +

Performance and Microstructure of Visible Light-Emitting Diodes Grown on High-Quality InGaP/GaP Epitaxial Transparent Substrates by MOVPE: *Andrew Y. Kim*¹; ¹MIT, Dept. of Mats. Sci. and Eng., MIT 13-4025, 77 Massachusetts Ave., Cambridge, Massachusetts 02139 USA

10:00 AM Break

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Photoreflectance Study of Phosphorus Passivation of GaAs: *Richard Beaudry*¹; Xiangang Xu¹; Jinsheng Hu¹; Simon P. Watkins¹; ¹Simon Fraser University, Dept. of Phys., 8888 University Dr., Burnaby, B.C. V5A 1S6 Canada

10:40 AM

Reversal of Electrical Stress Degradation in Fully Self-Aligned InP/GaAsSb/InP DHBTs by a Surface Treatment in Ozone: *Colombo R. Bolognesi*¹; *Noureddine Matine*¹; Georg Soerensen¹; Xiangang Xu²; Simon P. Watkins²; ¹Simon Fraser University, School of Eng. Sci., Compound Semiconductor Device Lab., 8888 University Dr., Burnaby, British Columbia V5A 1S6 Canada; ²Simon Fraser University, Dept. of Phys., 8888 University Dr., Burnaby, British Columbia V5A 1S6 Canada

11:00 AM +

Traps in Pseudomorphic InGaAs/AlGaAs/GaAs HEMTs Measured by Deep Level Capacitance and Current Transient Spectroscopy: *Evelyn N. Wang*¹; Mike Wojtowicz¹; Dwight C. Streit¹; ¹TRW, Inc., Electr. & Tech. Div., 1 Space Park, R6/2573, Redondo Beach, CA 90278 USA

11:20 AM +

Physical Evidence of Hydrogen Degradation of InP HEMTs: *Roxann R. Blanchard*¹; Jesus A. del Alamo¹; Albert Cornet²; ¹Massachusetts Institute of Tech., 60 Vassar St., Room 39-313, Cambridge, MA 02139 USA; ²Universitat de Barcelona, Facultat de Fisica, Av. Diagonal, 645-647, Barcelona E-08028 Spain

11:40 AM Late News

**Session DD. Non-Destructive Testing
and "In-Situ" Monitoring/Control**

Session Chairs: Kurt G. Eyink, Wright Patterson AFB, OH USA; John A. Roth, HRL Labs, Malibu, CA USA

1:30 PM

Characterization of P-Dopant Interdiffusion in 1.3 μm InGaAsP/InP Laser Structures using Modulation Spectroscopy: *A Jeager*¹; Fred H Pollak¹; C L Reynolds³; M Geva³; ¹Brooklyn College of CUNY, Phys. Dept., 3438N, 2900 Bedford Ave., Brooklyn, NY 11210 USA; ³Lucent Technologies, Bell Laboratories, Breinigsville, PA 18031 USA

1:50 PM

Room Temperature Polarized Photoreflectance Characterization of GaAlAs/InGaAs High Electron Mobility Transistor Structures Including the Influence of Strain Relaxation: *Ying-sheng Huang*¹; T. H. Chen¹; W. D. Sun²; Fred H. Pollak²; Mark Goorsky³; D. Streit⁴; M. Wojtowicz⁴; ¹National Taiwan University of Sci. and Tech., Dept. of Elect. Eng., 43 Keelung Rd. Sec. 4, Taipei 106 Taiwan ; ²Brooklyn College of CUNY, Phys. Dept., 2900 Bedford Ave., Brooklyn, NY 11210-2889 USA; ³UCLA, Dept. of Mats. Sci. and Eng., Los Angeles, CA 90095 USA; ⁴TRW, Electr. and Tech. Div., Redondo Beach, CA 90278 USA

2:10 PM +

Depth Defined Optoelectronic Modulation Spectroscopy: Chi-Hsin Chiu¹; *John Garth Swanson*¹; ¹Kings College London, Electronic Eng., Strand, London WC2R 2LS UK

2:30 PM +

Surface Photovoltage Spectroscopy of Two Dimensional Structures and Devices: *Nurit Ashkenasy*¹; Sanelia Solodky¹; Mark Leibovitch²; Yossi Rosenwaks¹; Irit Halkon²; Yoram Shapira¹; ¹Tel Aviv University, Dept. of Phys. Electr., Faculty of Eng., Ramat-Aviv, Tel-Aviv 69978 Israel; ²ELTA Electronics Industries, Ltd., P.O. Box 330, Ashdod 77102 Israel

2:50 PM +

UHV Contactless Capacitance-Voltage Characterization of Free Silicon Surfaces: *Toshiyuki Yoshida*¹; Hideki Hasegawa¹; Takamasa Sakai²; ¹Research Center for Interface Quantum Electronics (RCIQE) and Graduate School of Electronics and Information Eng., Hokkaido University, Kita-ku, Kita 13 Nishi 8, Sapporo, Hokkaido 060-8628 Japan; ²Dainippon Screen Manufacturing Co., Ltd., Fushimi-ku Hazukashi, Furukawa-cho 322, Kyouto, Kyouto-hu 612 Japan

3:10 PM Break

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Far UV Spectroscopic Reflectometry: *S. Lim*¹; S. Kriventsov¹; T. Mayer¹; T. Jackson¹; J. Freeouf²; ¹Penn State University, Center for Thin Film Devices and Electronic Mats. and Processing Research Lab., University Park, PA 16802; ²Interface Studies Inc., Katonah, NY 10536

3:50 PM

Spectroscopic Ellipsometry for Real-Time Control of Hetero-epitaxy of HgCdTe on Si: *L. A. Almeida*¹; Nibir K. Dhar²; J. David Benson³; Michael Martinka³; Andrew J. Stoltz¹; John H. Dinan³; ¹E-OIR Measurements, Inc., P.O. Box 1240, Spotsylvania, VA 22553-1240 USA; ²Army Research Laboratory, Adelphi, MD; ³Night Vision & Electronic Sensors Directorate, Fort Belvoir, VA 22060-5806 USA

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In Situ Controlled Electronic Properties of Low Temperature GaAs(001) for Two-Photon Absorbers: *J. Herfort*¹; G. Apostolopoulos¹; W. Ulrici¹; L. Däweritz¹; K. H. Ploog¹; M. Leitner²; P. Glas²; ¹Paul-Drude-Institut für Festkörperelektronik, Hausvogteiplatz 5-7, D-10117 Berlin Germany; ²Max-Born-Institut für Nichtlineare Optik und Kurzzeitspektroskopie, Rudower Chaussee 6, D-12474 Berlin Germany

4:30 PM +

Investigation of Indium Surface Segregation in Solid Source MBE Growth of In_xGa_{1-x}Sb: *David H. Tomich*¹; Kurt G. Eyink¹; Steve Fenstermaker²; Larry Grazulis²; Charles W. Tu³; ¹Air Force Research Laboratories, MLPO, 3005 P St. Ste. 6, Bldg. 651, WPAFB, OH 45433-7707 USA; ²Research Institute, University of Dayton, 300 College Park Dr., Dayton, OH 45469-0167 USA; ³University of California, San Diego, Dept. of Elect. and Comp. Eng., 9500 Gilman Dr., Mail Code 0407, La Jolla, CA 92093-0407 USA

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Improved Composition and Layer Interface Control by Modeling Knudsen Cell Heating Cycle: *Stephen J. Adams*¹; Kurt G. Eyink¹; ¹Air Force Research Laboratory, Wright-Patterson AFB, AFRL/MLPO, Wright-Patterson AFB, OH 45433-7750 USA

Friday PM, July 2, 1999

Session EE. Semiconductor Quantum Dots - Electronic Structures

Session Chairs: Mark Miller, University of Virginia, Dept. of Elect. Eng., Charlottesville, VA USA; Peter Sercel, University of Oregon, Phys. Dept., Eugene, OR USA

1:30 PM

Modified Fermi-Level Pinning of the (100) GaAs Surface Through InAs Quantum Dots in Different Stages of Overgrowth: *Carsten Walther*¹; H. Niehus¹; A. Thamm²; W. T. Masselink¹; ¹Humboldt University Berlin, Dept. of Phys., Invalidenstr. 110, Berlin 10115 Germany; ²Paul-Drude-Institut, Hausvogteiplatz 5-7, Berlin 10117 Germany

1:50 PM

Tunneling Spectroscopy of Electron States in Self-Assembled InAs Dots: *Kanji Yoh*¹; Yoshiyuki Kitasho¹; ¹Research Center for Interface Quantum Electronics, Hokkaido University, N 13, W 8, Kita-ku, Sapporo, Hokkaido 060 Japan

2:10 PM

Variation of the Potential Well of Self-Assembled InAs/GaAs Quantum Dots with Fixed Ground State Luminescence Energy:

*Markus Arzberger*¹; *Ulrich Käsberger*¹; *Liwen Chu*¹; *Gerhard Böhm*¹; *Markus-Christian Amann*¹; *Gerhard Abstreiter*¹; ¹Walter Schottky Institut, Am Coulombwall, Garching D-85748 Germany

2:30 PM

Electronic Detection of Optically Induced Charge Storage in Self Assembled InAs Quantum Dots:

*Doris Heinrich*¹; *Matthias Skalitz*¹; *Jonathan Finley*¹; *Jan Hoffmann*¹; *Artur Zrenner*¹; *Gerhard Böhm*¹; *Gerhard Abstreiter*¹; ¹Walter Schottky Institute, Technical University Munich, Am Coulombwall, D-85748 Garching Germany

2:50 PM

Dark Excitons Due to Direct Coulomb Interactions in Silicon Quantum Dots:

*Fernando A. Reboredo*¹; *Alberto Franceschetti*¹; *Alex Zunger*¹; ¹National Renewable Energy Laboratory, Solid State Theory, 1617 Cole Blvd., Golden, CO 80401

3:10 PM Break

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Photoluminescence of Strain-Induced Coupled Quantum Dot-Pairs:

*H.-W. Ren*¹; *T. Okuno*²; *K. Nishibayashi*²; *J.-S. Lee*¹; *S. Sugou*¹; *M. Sugisaki*¹; *Y. Masumoto*¹; ¹Single Quantum Dot Project, ERATO, JST, c/o NEC Corp., 34 Miyukigaoka, Tsukuba 305-8501 Japan; ²University of Tsukuba, Institute of Phys., Tsukuba 305-8571 Japan

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Experimental Determination of Intra-level Relaxation Time in Quantum Dots with Different Energy Level Spacing:

*H. Koskenvaara*¹; *M. Sopanen*¹; *H. Lipsanen*¹; *M. Brasken*²; *M. Lindberg*²; ¹Helsinki University of Tech., Optoelectronics Lab., Espoo FIN-02150 Finland; ²Abo Akademi University, Dept. of Phys., Turku FIN-20500 Finland

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Band Structure Modification of InP Dots at High Pressure:

*Linshi Miao*¹; *Dinesh Patel*¹; *Carmen S. Menoni*¹; *Olga I. Micic*²; *Arthur J. Nozik*²; ¹Colorado State University, Elect. and Comp. Eng., Fort Collins, CO 80523-1373 USA; ², National Renewable Energy Laboratory, Golden, CO 80401 USA

Session FF. Issues of Dopants and Defects in Nitrides

Session Chairs: Christian Wetzel, Meijo University, High Tech Research Center, Tempaku-ku, Nagoya, Japan; Alan Wright, Sandia National Laboratories, Albuquerque, NM USA

1:30 PM +

Influence of Dislocations in InGaN/GaN Quantum Well Grown by Metalorganic Chemical Vapor Deposition: *Tomoya Sugahara*¹;

¹The University of Tokushima, Sakai Lab. Dept. of Elect. and Electr. Eng., 2-1 Minami-Josanjima, Tokushima 770-8506 Japan

1:50 PM

Atomic Scale Analysis of Defect Structures and Properties in III-Nitride Materials by Z-Contrast Imaging and EELS in STEM:

*Yan Xin*¹; Nigel D. Browning¹; Steve J. Pennycook²; Siva Sivananthan¹; Robert Sporken³; F. Omnes⁴; B. Beaumont⁴; J. P. Faurie Faurie⁴; Pierre Gibart⁴; ¹University of Illinois at Chicago, Phys., 845 W Taylor St., Chicago, IL 60607 USA; ²Oak Ridge National Laboratory, Solid State Div., Oak Ridge, TN 37831 USA; ³Facultes Universitaires Notre-Dame de La Paix, Laboratoire L.I.S.E Belgium; ⁴CRHEA-CNRS, rue Bernard Gregory, 06560 Valbonne France

2:10 PM

Investigation of the Formation of the 2.8eV PL Band in P-Type GaN: *Fatemeh Shahedipour*¹; Bruce W. Wessels¹;

¹Northwestern University, Mats. Sci. and Eng., 2225 N. Campus Dr., Evanston, IL 60208

2:30 PM

Effect of Threading Dislocations, Mg-Doping and Etching on the Photoconductivity Spectra of GaN: *John T. Torvik*¹; J. I. Pankove¹;

S. Nakamura²; I. Grzegory³; S. Porowski³; ¹Astralux, Inc., 2500 Central Ave., Boulder, CO 80301 USA; ²Nichia Chemical Ind., R&D Dept., 491 Oka Kaminaka, Anan, Tokushima 774 Japan; ³Polish Academy of Sciences, High Pressure Research Center, Sokolowska 29/37, 01-42, Warsaw Poland

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Optically Detected Magnetic Resonance Study of Defects in Undoped, Be-Doped, and Mg-Doped GaN: *Friedrich Karl Koschnick*¹;

Karsten Michael¹; Johann Martin Spaeth¹; Bernard Beaumont²; Pierre Gibart²; Enrique Calleja³; Elias Munoz³; ¹University of Paderborn, Phys. Dept., Warburger Str. 100, Paderborn 33098 Germany; ²CRHEA-CNRS, Valbonne France; ³University of Madrid, Madrid Spain

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Optical Properties of Rare Earth Doped GaN Grown by MBE: *Andrew J. Steckl*¹; ¹University of Cincinnati, ECE/CS Dept., P.O. Box 210030, 899 Rhodes Hall, Cincinnati, OH 45221-0030 USA

3:50 PM

Near-Surface Cathodoluminescence Spectroscopy of Erbium Doped AlN: *Alexander P. Young*¹; Stephen H. Goss²; Leonard J. Brillson¹; J. D. MacKenzie³; C. R. Abernathy³; ¹Ohio State University, Elect. Eng., 205 Dreese Lab., 2015 Neil Ave., Columbus, OH 43210-1272 USA; ²Ohio State University, Center for Mats. Research, 205 Dreese Lab., 2015 Neil Ave., Columbus, OH 43210-1272 USA; ³University of Florida, Mats. Sci. and Eng., Gainesville, FL 32611 USA

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Isoelectronic Doping of Gallium Nitride with Arsenic: *Peter H Mitev*¹; M. Gherasimova¹; B. Gaffey¹; L. J. Guido¹; ¹Yale University, Center For Microelect. Mats. and Structures, P.O. Box 208284, New Haven, CT 06520-8284 USA

4:30 PM

Yellow Luminescence and Electronic Conductivity in GaN: *Ilan Shalish*¹; Leeor Kronik¹; Yoram Shapira¹; Joseph Salzman²; ¹Tel-Aviv University, Dept. of Phys. Electr., Tel-Aviv 69978 Israel; ²Technion-Israel Institute of Tech., Elect. Eng., Solid-State Institute and Microelect. Center, Haifa 32000 Israel

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Electric Force Microscopy of Induced Charges and Surface Potentials in GaN Modified by Light and Strain: *P. M. Bridger*¹; Zvonimir Z. Bandic¹; Eric C. Piquette¹; T. C. McGill¹; ¹California Institute of Tech., Applied Phys., Mail Stop 128-95, Pasadena, CA 91125 USA

Friday PM, July 2, 1999

Session GG. Epitaxy of II-VI and Chalcopyrites

Session Chair: Charles Tu, University of California-San Diego, LaJolla, CA USA

1:30 PM

Homoepitaxy of ZnTe by MBE: *J. H. Chang*¹; H. M. Wang¹; K. Arai¹; M. W. Cho¹; K. Godo¹; H. Makino¹; T. Hanada¹; K. Satoh²; O. Oda²; T. Yao¹; ¹Tohoku University, Institute for Mats. Research, 2-1-1 Katahira, Aoba-ku, Sendai, 980-8577 Japan; ²Central R&D Laboratory, Japan Energy Corporation, Japan

1:50 PM

High Quality ZnSe Layers with an Atomically Flat Surface Grown on GaAs(001) by Molecular Beam Epitaxy: *Kenat Arai*¹; Akihiro Ohtake²; Takashi Hanada¹; Tetsuji Yasuda³; Takafumi Yao¹; ¹Tohoku University, Institute for Mats. Research, 2-1-1, Katahira,

Aoba, Sendai 980-8577 Japan; ²Joint Research Center for Atom Technology, Angstrom Technology Partnership, 1-1-4, Higashi, Tsukuba 305-0046 Japan; ³Joint Research Center for Atom Technology, National Institute for Advanced Interdisciplinary Research, 1-1-4, Higashi, Tsukuba 305-0046 Japan

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Growth and Characterization of Multiple Quantum Wells of ZnSn(P_xAs_{1-x})/GaAs: *Georgiy A. Seryogin*¹; Sergey A. Nikishin¹; Henryk Temkin¹; ¹Texas Tech University, Dept. of Elect. Eng., MS3102, Lubbock, TX 79407 USA

2:30 PM

Epitaxial Growth of γ -In₂Se₃ Films with a Defect Wurtzite Structure by Molecular Beam Epitaxy: *Tomohiko Ohtsuka*¹; Tamotsu Okamoto²; Akira Yamada¹; Makoto Konagai¹; ¹Tokyo Institute of Tech., Dept. of Elect. and Electr. Eng., Faculty of Eng., 2-12-1, O-okayama, Meguro-ku, Tokyo 152-8552 Japan; ²Tokyo Institute of Tech., Research Center for Quantum Effect Electronics, 2-12-1, O-okayama, Meguro-ku, Tokyo 152-8552 Japan

2:50 PM Late News

3:10 PM Break

Friday PM, July 2, 1999

Session HH. Epitaxy of Si, III-V, Oxides

Session Chair: Colombo Bolognesi, Simon Fraser University, Dept. of Elect. Eng., Burnaby, BC Canada

1:30 PM

Characterization of Silicon Atomic-Layer-Epitaxy by an Atomic-Force Microscope: *Keiji Ikeda*¹; Yasuo Satoh¹; Satoshi Sugahara¹; Masakiyo Matsumura¹; ¹Tokyo Institute of Tech., Dept. of Physical Electronics, 2-12-1, O-okayama, Meguro-ku, Tokyo 152-8550 Japan

1:50 PM

Surface Phases of InP (001) in the MOVPE Process: *Robert F. Hicks*¹; Lian Li¹; Byung-Kwon Han¹; Daniel Law¹; Qiang Fu¹; Connie Li¹; ¹University of California, Chem. Eng. Dept., Los Angeles, CA 90095

2:10 PM

The Structure of Aluminum Antimonide Surfaces Grown by Molecular Beam Epitaxy: *Allan S. Bracker*¹; William Barvosa-Carter¹; James C. Culbertson¹; Brian R. Bennett¹; Lloyd J. Whitman¹; Benjamin V. Shanabrook¹; ¹Naval Research Laboratory, Electronics Sci. and Tech. Div., Code 6876, 4555 Overlook Ave., SW, Washington, DC 20375 USA

2:30 PM

MBE Growth of ZnO Films on GaN and Characterization: *H. J. Ko*¹; *Y. F. Chen*¹; *S. K. Hong*¹; *T. Yao*¹; ¹Tohoku University, Institute for Mats. Research, 2-1-1 Katahira, Aoba-ku, Sendai 980 Japan

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Plasma Assisted Molecular Beam Epitaxy and Characterization of the $\text{Mg}_x\text{Zn}_{1-x}\text{O}/\text{ZnO}$ Hetero-Structures: *Yefan Chen*¹; *Takafumi Yao*¹; *Yosaburo Segawa*²; *Hang-ju Ko*¹; *Soon-ku Hong*¹; ¹Tohoku University, Institute for Mats. Research, Katahira 2-1-1, Aoba-ku, Sendai, Miyagi-ken 980-0821 Japan; ²The Institute of Physical and Chemical Research, Photon Dynamics Research Center, Koeji 19-1399, Nagamachi Aoba-ku, Sendai, Miyagi-ken Japan

3:10 PM Break